

TEST REPORT

Applicant Name: Koki Holdings Co., Ltd.
Address: Shinagawa Intercity Tower A, 18th Floor 15-1, Konan
2-chome, Minato-ku Tokyo, Japan
Report Number: 2501U26762E-RF-07A

Test Standard (s)

Item 19 of Article 2 Paragraph 1

Sample Description

Product Type: Tracker Pro
Model No.: C25ME
Multiple Model(s) No.: N/A
Trade Mark: HIKOKI
Date Received: 2025-06-18
Issue Date: 2025-10-01

Test Result:	Pass▲
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▲ In the configuration tested, the EUT complied with the standards above.

Prepared and Checked By:

Jim Cheng

Jim Cheng
RF Engineer

Approved By:

Nancy Wang

Nancy Wang
RF Supervisor

Note: The information marked * is provided by the applicant, the laboratory is not responsible for its authenticity and this information can affect the validity of the result in the test report. Customer model name, addresses, names, trademarks etc. are included.

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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Revision
0	2501U26762E-RF-07A	Original Report	2025-10-01

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

Technical Parameters	Radio Type	BLE
	Modulation Type	GFSK
	Frequency Range	2402-2480MHz
	Rated Output Power	3.00mW for BLE 1M/2M
	Antenna Gain[#]	-6.34dBi (It is provided by the applicant)
Nominal Power Supply		DC 3V from Coin Cell
Sample serial number		34Q4-2 (Assigned by BACL, Shenzhen)
Sample/EUT Status		Good condition
Normal/Extreme Condition		LV: Low Voltage: 2.7V _{DC} NV: Normal Voltage: 3V _{DC} HV: High Voltage: 3.3V _{DC}
Adapter Information		N/A

Objective

The objective of the manufacturer is to demonstrate compliance with Radio Law of Japan item 19 of Article 2 Paragraph 1, rules and limits for this device including:

- Frequency Error
- Occupied Bandwidth
- Transmitter Spurious Emission and Unwanted Emission Intensity
- Antenna Output Power And Output Power Tolerance
- Receiver Spurious Emission Strength
- Interference Prevention Function
- Construction Protection Confirmation

Test Method

MIC Notice No.88 Appendix No.43

Measurement Uncertainty

Item	Expanded Measurement uncertainty
Frequency error	56.6Hz(k=2, 95% level of confidence)
Occupied Channel Bandwidth	109.2kHz(k=2, 95% level of confidence)
RF output power, conducted	0.86dB(k=2, 95% level of confidence)
Unwanted Emission, conducted	1.60dB(k=2, 95% level of confidence)
Duty Cycle	±1%
Temperature	±1°C
Supply voltages	±0.4%
Humidity	±1%

Note: The extended uncertainty given in this report is obtained by combining the standard uncertainty times the coverage factor K with the 95% confidence interval. Otherwise required by the applicant or Product Regulations, Decision Rule in this report did not consider the uncertainty.

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 5F(B-West) , 6F, 7F, the 3rd Phase of Wan Li Industrial Building D, Shihua Rd, FuTian Free Trade Zone, Shenzhen, China.

Each test item follows test standards and with no deviation.

EUT TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a testing mode by some software.

For BLE mode, 40 channels are provided for testing:

Channel	Frequency(MHz)	Channel	Frequency(MHz)
0	2402	20	2442
1	2404	21	2444
...	...	...	...
...	...	...	...
...	...	...	...
18	2438	38	2478
19	2440	39	2480

EUT was tested with channel 0, 19 and 39.

EUT Exercise Software

Exercise Software#	nRF Connect for Desktop		
Power Level#			
Mode	Low Channel	Middle Channel	High Channel
BLE 1M	8	8	8
BLE 2M	8	8	8

Equipment Modifications

No modification was made to the EUT tested.

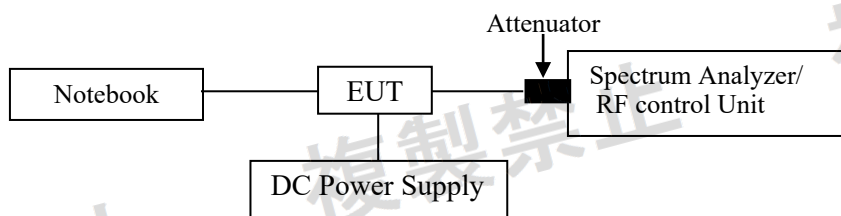
Support Equipment List and Details

Manufacturer	Description	Model	Serial Number
DELL	Notebook	PC-202404261620	00330-80000-00000-AA404
Instek	DC Power Supply	GPS-3030DD	EM832096

External I/O Cable

Cable Description	Length(m)	From/Port	To
Unshielded Detachable USB cable	1.0	EUT	Notebook
Unshielded Detachable DC cable*2	1.0	EUT	DC Power Supply

Configuration of Test Setup



SUMMARY OF TEST RESULTS

MIC Notice No.88 Appendix No.43 Article 2, Paragraph 1, Item 19	Description of Test	Result
1	Frequency Error	Compliant
2	Occupied Bandwidth	Compliant
3	Transmitter Spurious Emission and Unwanted Emission Intensity	Compliant
4	Antenna Output Power and Output Power Tolerance	Compliant
5	Receiver Spurious Emission and Unwanted Emission Intensity	Compliant
6	Transmission Antenna Gain	Not Applicable
7	Carrier sense capability	Not Applicable**
8	Transmission Radiation Angle Width	Not Applicable
9	Frequency Hopping Dwell Time	Not Applicable*
10	Interference Prevention Function	Compliant
11	Construction Protection Confirmation	Compliant

Not Applicable* -Testing is only required for FHSS system devices.

Not Applicable**-The OBW of EUT is less than 26 MHz.

Not Applicable - This test item was not required for the output power less than 12.14 dBm (E.I.R.P)

TEST EQUIPMENT LIST

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date	Calibration Authority	Calibration Method
Tonscend	RF control Unit	JS0806-2	19D8060154	2024/08/06	2025/08/05	BACL Cal	c)
Rohde & Schwarz	Spectrum Analyze	FSU26	200982	2024/09/20	2025/09/19	BACL Cal	c)
Rohde & Schwarz	Spectrum Analyzer	FSV40-N	102259	2024/12/04	2025/12/03	BACL Cal	c)
Rohde&Schwarz	Wideband Radio Communication Tester	CMW500	141718	2024/08/06	2025/08/05	BACL Cal	c)
Unknown	10dB Attenuator	Unknown	F-03-EM014	2025/06/26	2026/06/25	BACL	d)

Note: Calibration Method

a) Calibration conducted by the National Institute of Information and Communications Technology (NICT) or a designated calibration agency under Article 102-18 paragraph (1)

b) Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Law (Law No. 51 of 1992) ~Japan Calibration Service System~

c) Calibration conducted in foreign countries, which shall be equivalent to the calibration conducted by the NICT or a designated calibration agency under Article 102-18 paragraph (1)

d) Calibration conducted by using other equipment that listed above from a) to c)

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

REQUIREMENTS AND TEST PROCEDURES

Frequency Error

Limit

50 ppm or below

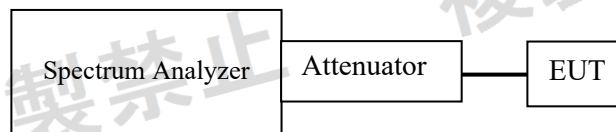
Test Procedure

Set the EUT to the measurement frequency without modulation.
Setting of SA is following as:

- Center Frequency: Frequency to measure
- RBW: 1 kHz, VBW: 3 kHz
- Span: 300 kHz
- Sweep time: Auto
- Log scale: 10dB/Div, Data points: 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak
- Sweep mode: Single Sweep
- Marker: Spot

Record the peak spot frequency.

If the EUT can't set at un-modulation mode, measure the 10dBc center frequency.



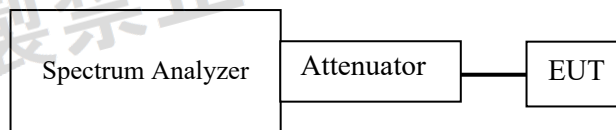
Occupied Bandwidth

Limit

- Occupied bandwidth: FH $\leq$ 83.5 MHz; OFDM, DS $\leq$ 26 MHz; Others $\leq$ 26 MHz

Test Procedure

1. Setting of SA is following as:
 - Center Frequency: Frequency to measure
 - RBW: 30 kHz, VBW: 30 kHz
 - Sweep time: Auto
 - Log scale: 10dB/Div, Data points: 400 points or more
 - Reference level: Enough level for maximum dynamic range
 - Detection: Positive Peak
 - Sweep mode: Continuous Sweep
 - Marker: Spot
2. EUT have transmitted the maximum modulation signal and fixed channelize. SA set to 99% of occupied bandwidth to measure occupied bandwidth.



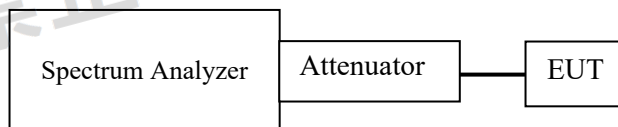
Transmitter Spurious Emission Strength and Unwanted Emission Intensity

Limit

- $f < 2387 \text{ MHz}$, $f > 2496.5 \text{ MHz}$: $\leq 2.5 \mu\text{W/MHz}$
- $2387 \text{ MHz} \leq f \leq 2400 \text{ MHz}$; $2483.5 \text{ MHz} < f \leq 2496.5 \text{ MHz}$: $\leq 25 \mu\text{W/MHz}$

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be in continuously transmitting mode.

Spectrum Analyzer Conditions

- Span: Measuring Frequency Range
- RBW: 1MHz (frequency range; 1GHz over), 100kHz (frequency range; 30MHz to 1GHz)
- VBW: Same as RBW (1MHz or 100kHz)
- Sweep time: Auto (Minimum time to ensure measurement accuracy.)
- Data points : 400 points or more
- Reference level: Enough level for maximum dynamic range
- Detection: Positive Peak

If the measured value is under the technical standard value, do not need to measure more detail.

Antenna Output Power and Antenna Power Tolerance

Limit

Antenna power:

- ≤ 10 mW/MHz (OFDM, DSSS from 2400-2483.5 MHz)
- ≤ 10 mW (other from 2400-2483.5 MHz)

The Output Power Tolerance must be within +20%, -80%.

E.i.r.p:

- ≤ 12.14 dBm/MHz (OFDM (20MHz system), DSSS form 2400-2483.5MHz)
- ≤ 9.13 dBm/MHz (OFDM(40MHz system) from 2400-2483.5MHz)
- ≤ 12.14 dBm (other from 2400-2483.5MHz)

Test Procedure

Step 1: Measure the total power by Power Meter in a state of hopping mode or non-hopping mode (with Average Sensor)

Step 2: If it's the burst wave, set the power meter to measure averaging across the burst transmit on period.

Step 3: Record the reading on power meter as antenna output power.

Test Setup Block diagram



Note: the power meter was integrated in the RF control Unit.

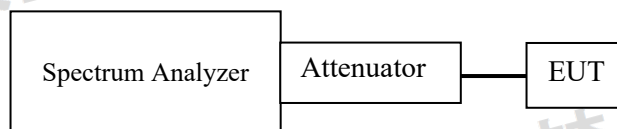
Receiver Spurious Emission and Unwanted Emission Intensity

Limit

- $\leq 4\text{nW}$ ($30\text{ MHz} \leq f \leq 1000\text{ MHz}$)
- $\leq 20\text{ nW}$ ($f \geq 1\text{ GHz}$)

Test Procedure

Measurement System Diagram



Conditions of Application Equipment (EUT)

- The modulation state shall be “continuous receiving mode”.

Spectrum Analyzer Conditions

- Start Frequency: Start Frequency of frequency range to measure (30MHz or 1GHz)
- Stop Frequency: Stop Frequency of frequency range to measure (1GHz or 12.5GHz)
- Span: AUTO (Measurement Range)
- RBW: 100 kHz, VBW: 100 kHz for Frequency < 1 GHz
- RBW: 1MHz, VBW: 1MHz for Frequency > 1 GHz
- Sweep time: AUTO or more
- Sweep mode: Auto Sweep
- Detection: Positive Peak
- Reference Level: Enough level for maximum dynamic range

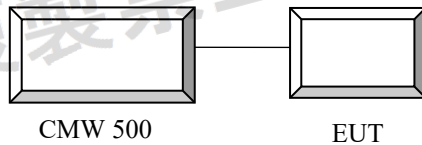
Interference Prevention Function

Requirement

The EUT shall have the interference prevention capability to transmit or to receive the identification automatically, so that sender and receiver shall exclude other equipment.

Test Procedure

Measurement System Diagram



In the case that the EUT has the function of automatically transmitting the identification code:

1. Transmit the predetermined identification codes from EUT
2. Check the transmitted identification codes with the demodulator.

In the case of receiving the identification codes:

1. Transmit the predetermined identification codes from the counterpart.
2. Check if communication is normal
3. Transmit the signal other than predetermined ID codes from the counterpart.
4. Check if the EUT stops the transmission, or if it displays that identification codes are different from the predetermined ones.

TEST DATA AND RESULTS**Frequency Error****Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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Test Condition: NV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2402.04200	17.49	± 50	Pass
	2440	2440.04275	17.52		Pass
	2480	2480.04350	17.54		Pass

Test Condition: LV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2402.04163	17.33	± 50	Pass
	2440	2440.04238	17.37		Pass
	2480	2480.04275	17.24		Pass

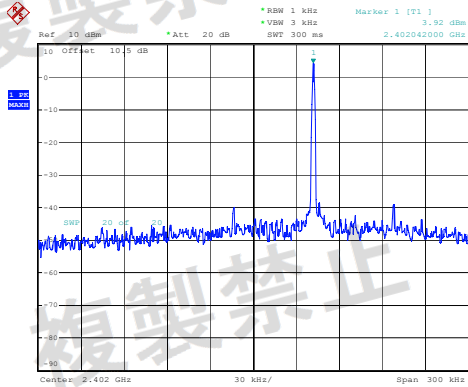
Test Condition: HV

Mode	Frequency (MHz)	Measure Frequency (MHz)	Frequency Tolerance (ppm)	Limit (ppm)	Verdict
Single Carrier	2402	2402.04163	17.33	± 50	Pass
	2440	2440.04238	17.37		Pass
	2480	2480.04313	17.39		Pass

Frequency Tolerance = (Measure Frequency - Frequency)/Frequency*10⁶

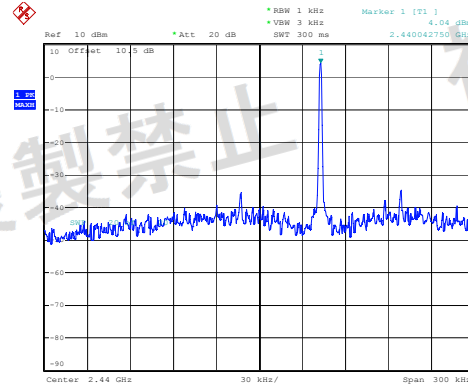
Test Condition: NV

2402MHz



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:14:35

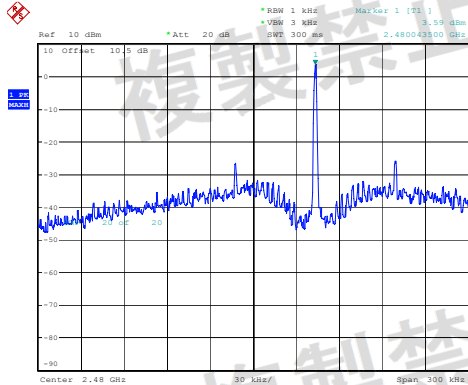
2440MHz



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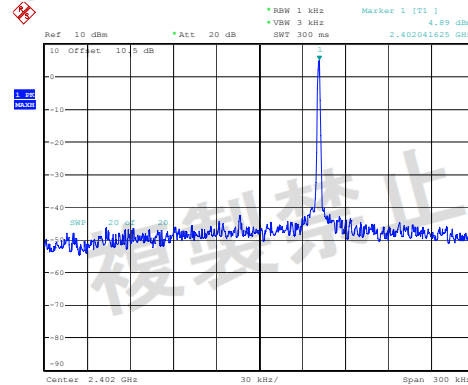
Test Condition: LV

2480MHz



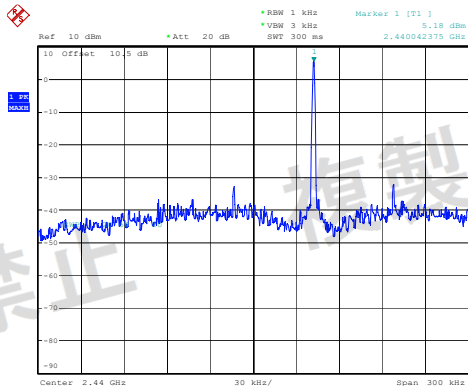
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Date: 4.JUL.2025 14:15:26

2402MHz



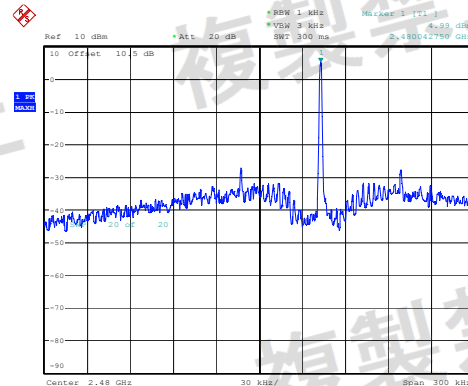
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Date: 4.JUL.2025 16:51:19

2440MHz



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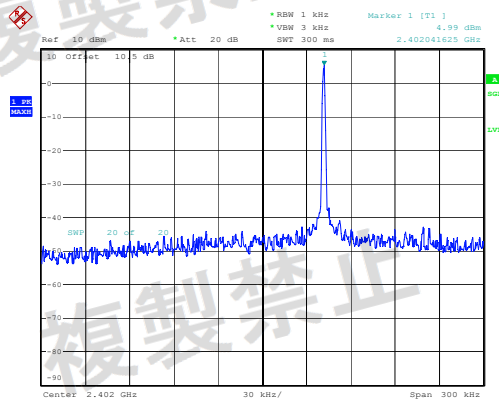
2480MHz



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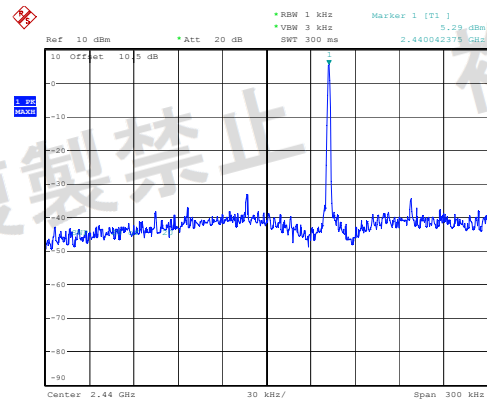
Test Condition: HV

2402MHz



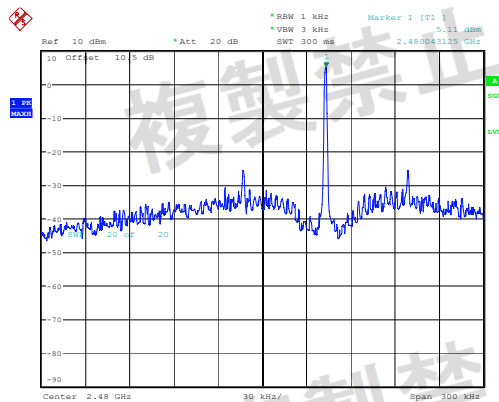
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:34:20

2440MHz



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:34:54

2480MHz



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:35:26

Occupied Bandwidth**Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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Test Condition: NV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.050	1.050	1.053	≤ 26	Pass
BLE 2M	2.081	2.088	2.088		Pass

Test Condition: LV

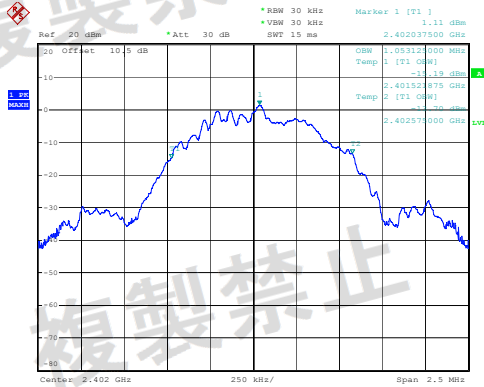
Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.053	1.053	1.053	≤ 26	Pass
BLE 2M	2.081	2.088	2.088		Pass

Test Condition: HV

Mode	Occupied bandwidth (MHz)			Limit(MHz)	Verdict
	Low Channel	Middle Channel	High Channel		
BLE 1M	1.053	1.053	1.053	≤ 26	Pass
BLE 2M	2.081	2.088	2.088		Pass

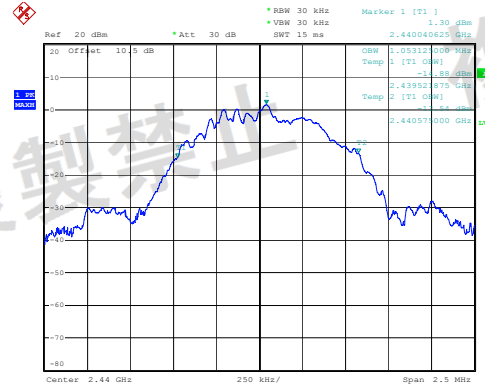
Test Condition: HV

BLE 1M_Low Channel



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:19:18

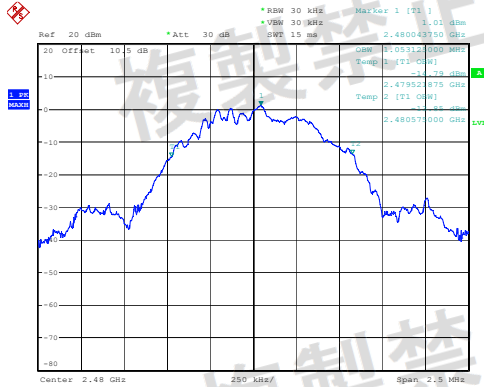
BLE 1M_Middle Channel



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:23:59

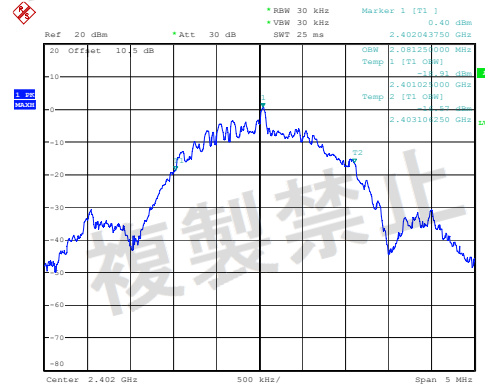
Test Condition: NV

BLE 1M_High Channel



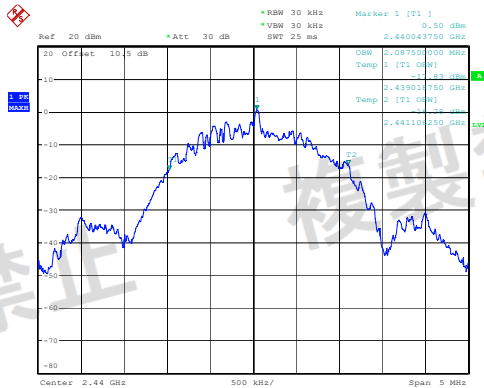
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:26:22

BLE 2M_Low Channel



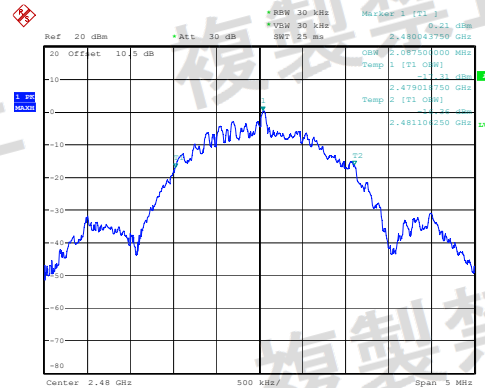
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:18:27

BLE 2M_Middle Channel

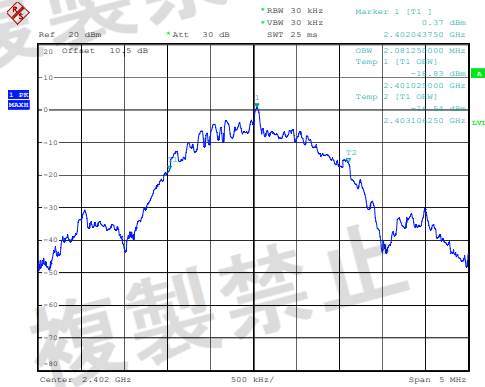


ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:25:26

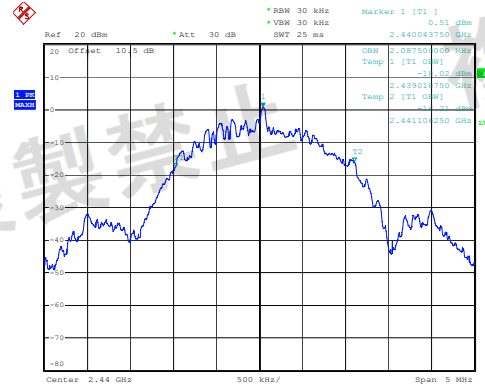
BLE 2M_High Channel



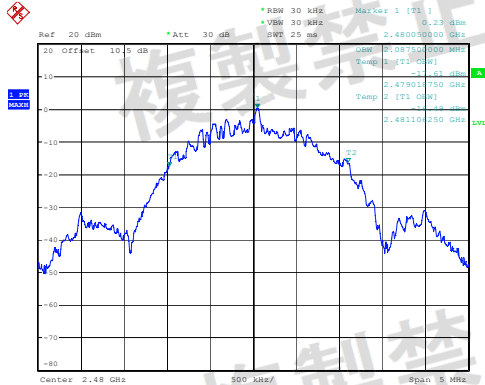
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Date: 4.JUL.2025 15:27:17

Test Condition: LV**BLE 2M_Low Channel**

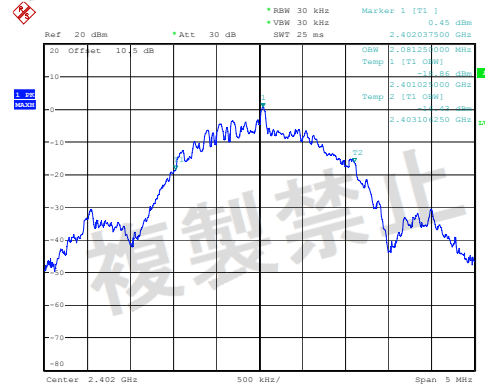
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:12:53

BLE 2M_Middle Channel

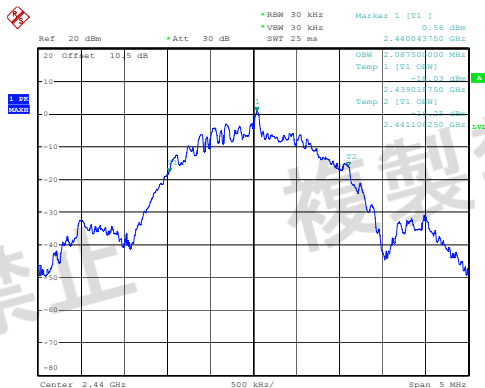
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:14:27

Test Condition: HV**BLE 2M_High Channel**

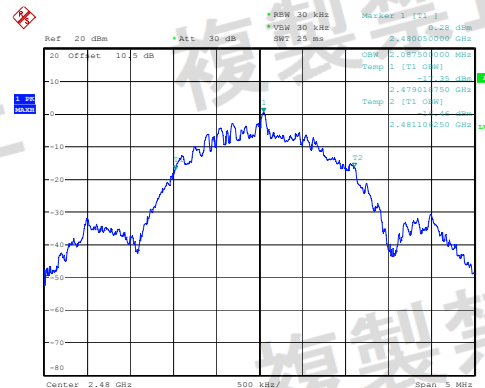
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:16:05

BLE 2M_Low Channel

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:18:09

BLE 2M_Middle Channel

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:30:34

BLE 2M_High Channel

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:32:15

Transmitter Spurious Emission and Unwanted Emission Intensity**Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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Test Condition: Normal, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	679.094	-43.71	0.043	0.25	Pass
	Band II (1MHz)	1000	2387	2209.286	-38.66	0.136	2.50	Pass
	Band III (1MHz)	2387	2400	2399.980	-16.10	24.547	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2490.169	-37.29	0.187	25	Pass
	Band V (1MHz)	2496.5	12500	11073.074	-36.99	0.200	2.50	Pass
Middle	Band I (100kHz)	30	1000	735.896	-43.49	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	2136.396	-38.57	0.139	2.50	Pass
	Band III (1MHz)	2387	2400	2388.210	-38.15	0.153	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2490.872	-37.40	0.182	25	Pass
	Band V (1MHz)	2496.5	12500	12069.419	-36.84	0.207	2.50	Pass
High	Band I (100kHz)	30	1000	345.080	-43.39	0.046	0.25	Pass
	Band II (1MHz)	1000	2387	2062.811	-38.19	0.152	2.50	Pass
	Band III (1MHz)	2387	2400	2399.974	-37.14	0.193	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.572	-30.09	0.979	25	Pass
	Band V (1MHz)	2496.5	12500	10146.824	-36.92	0.203	2.50	Pass

Test Condition: Normal, BLE 2M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	825.225	-42.66	0.054	0.25	Pass
	Band II (1MHz)	1000	2387	1722.656	-33.05	0.495	2.50	Pass
	Band III (1MHz)	2387	2400	2399.997	-18.23	15.031	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2495.810	-37.35	0.184	25	Pass
	Band V (1MHz)	2496.5	12500	10877.811	-36.91	0.204	2.50	Pass
Middle	Band I (100kHz)	30	1000	335.856	-43.43	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	2370.339	-38.83	0.131	2.50	Pass
	Band III (1MHz)	2387	2400	2392.166	-37.49	0.178	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2485.829	-38.12	0.154	25	Pass
	Band V (1MHz)	2496.5	12500	11048.041	-37.28	0.187	2.50	Pass
High	Band I (100kHz)	30	1000	53.303	-42.55	0.056	0.25	Pass
	Band II (1MHz)	1000	2387	1728.904	-33.54	0.443	2.50	Pass
	Band III (1MHz)	2387	2400	2399.694	-38.12	0.154	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.559	-29.82	1.042	25	Pass
	Band V (1MHz)	2496.5	12500	10772.669	-37.06	0.197	2.50	Pass

Test Condition: LV, BLE 1M

Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	864.550	-43.46	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	1726.821	-36.99	0.200	2.50	Pass
	Band III (1MHz)	2387	2400	2400.000	-17.03	19.815	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2490.280	-37.72	0.169	25	Pass
	Band V (1MHz)	2496.5	12500	11944.250	-36.50	0.224	2.50	Pass
Middle	Band I (100kHz)	30	1000	653.849	-43.44	0.045	0.25	Pass
	Band II (1MHz)	1000	2387	1720.574	-32.88	0.515	2.50	Pass
	Band III (1MHz)	2387	2400	2399.174	-38.16	0.153	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2488.250	-37.76	0.167	25	Pass
	Band V (1MHz)	2496.5	12500	3517.878	-36.57	0.220	2.50	Pass
High	Band I (100kHz)	30	1000	158.654	-43.88	0.041	0.25	Pass
	Band II (1MHz)	1000	2387	2221.782	-38.56	0.139	2.50	Pass
	Band III (1MHz)	2387	2400	2391.984	-37.85	0.164	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.604	-29.59	1.099	25	Pass
	Band V (1MHz)	2496.5	12500	3447.784	-36.95	0.202	2.50	Pass

Test Condition: LV, BLE 2M

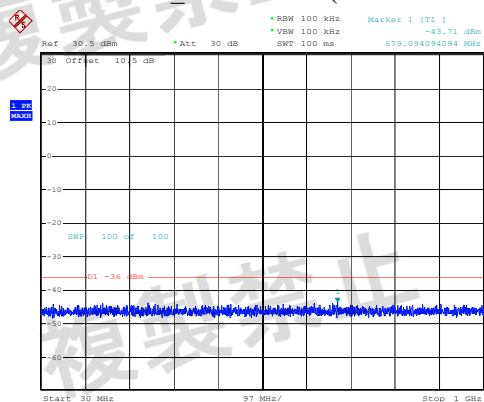
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	830.566	-42.13	0.061	0.25	Pass
	Band II (1MHz)	1000	2387	2370.339	-38.14	0.153	2.50	Pass
	Band III (1MHz)	2387	2400	2399.990	-18.48	14.191	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.967	-37.56	0.175	25	Pass
	Band V (1MHz)	2496.5	12500	10171.858	-36.37	0.231	2.50	Pass
Middle	Band I (100kHz)	30	1000	245.070	-43.60	0.044	0.25	Pass
	Band II (1MHz)	1000	2387	2296.755	-39.17	0.121	2.50	Pass
	Band III (1MHz)	2387	2400	2390.130	-38.11	0.155	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2492.733	-37.82	0.165	25	Pass
	Band V (1MHz)	2496.5	12500	3512.872	-36.91	0.204	2.50	Pass
High	Band I (100kHz)	30	1000	889.795	-36.35	0.232	0.25	Pass
	Band II (1MHz)	1000	2387	1570.628	-38.97	0.127	2.50	Pass
	Band III (1MHz)	2387	2400	2388.223	-38.15	0.153	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.578	-29.82	1.042	25	Pass
	Band V (1MHz)	2496.5	12500	10747.635	-36.57	0.220	2.50	Pass

Test Condition: HV, BLE 1M

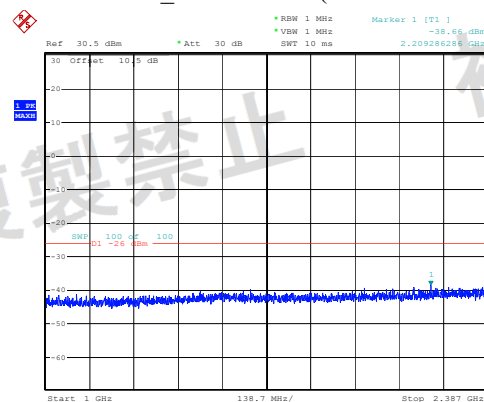
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	622.292	-43.41	0.046	0.25	Pass
	Band II (1MHz)	1000	2387	2322.440	-38.96	0.127	2.50	Pass
	Band III (1MHz)	2387	2400	2400.000	-16.75	21.135	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.897	-37.21	0.190	25	Pass
	Band V (1MHz)	2496.5	12500	2601.642	-36.97	0.201	2.50	Pass
Middle	Band I (100kHz)	30	1000	140.691	-43.81	0.042	0.25	Pass
	Band II (1MHz)	1000	2387	2082.943	-38.73	0.134	2.50	Pass
	Band III (1MHz)	2387	2400	2396.500	-38.46	0.143	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.897	-37.34	0.185	25	Pass
	Band V (1MHz)	2496.5	12500	10241.953	-36.78	0.210	2.50	Pass
High	Band I (100kHz)	30	1000	239.730	-43.14	0.049	0.25	Pass
	Band II (1MHz)	1000	2387	2184.295	-38.81	0.132	2.50	Pass
	Band III (1MHz)	2387	2400	2399.336	-37.81	0.166	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.546	-30.49	0.893	25	Pass
	Band V (1MHz)	2496.5	12500	9490.939	-37.17	0.192	2.50	Pass

Test Condition: HV, BLE 2M

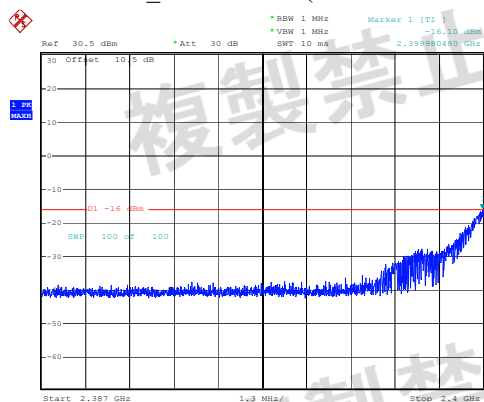
Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm/RBW)	Result (μW/RBW)	Limit (μW/RBW)	Verdict
		Start (MHz)	Stop (MHz)					
Low	Band I (100kHz)	30	1000	556.266	-42.76	0.053	0.25	Pass
	Band II (1MHz)	1000	2387	1711.549	-38.53	0.140	2.50	Pass
	Band III (1MHz)	2387	2400	2399.990	-18.62	13.740	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2493.904	-37.27	0.187	25	Pass
	Band V (1MHz)	2496.5	12500	3517.878	-28.26	1.493	2.50	Pass
Middle	Band I (100kHz)	30	1000	978.153	-43.88	0.041	0.25	Pass
	Band II (1MHz)	1000	2387	2316.886	-38.95	0.127	2.50	Pass
	Band III (1MHz)	2387	2400	2387.469	-38.47	0.142	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2494.171	-37.52	0.177	25	Pass
	Band V (1MHz)	2496.5	12500	3517.878	-28.43	1.435	2.50	Pass
High	Band I (100kHz)	30	1000	631.031	-43.77	0.042	0.25	Pass
	Band II (1MHz)	1000	2387	2360.621	-38.80	0.132	2.50	Pass
	Band III (1MHz)	2387	2400	2389.050	-38.28	0.149	25	Pass
	Band IV (1MHz)	2483.5	2496.5	2483.786	-30.11	0.975	25	Pass
	Band V (1MHz)	2496.5	12500	3517.878	-29.38	1.153	2.50	Pass

Test Condition: NV**BLE 1M_Low Channel(30MHz~1GHz)**

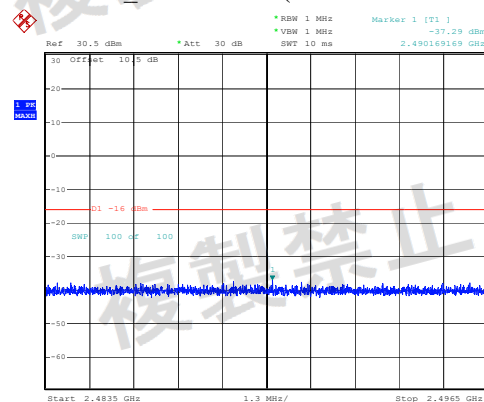
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:03:38

BLE 1M_Low Channel(1GHz~2.387GHz)

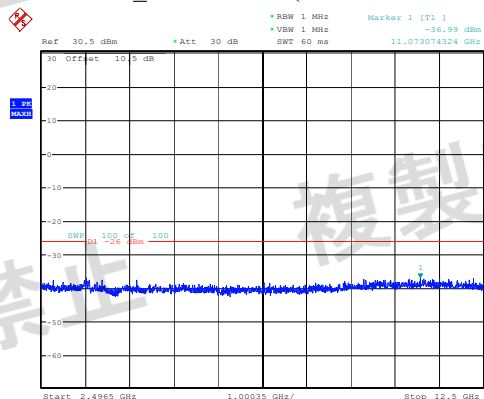
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Date: 4.JUL.2025 15:03:49

BLE 1M_Low Channel(2.387GHz~2.4GHz)

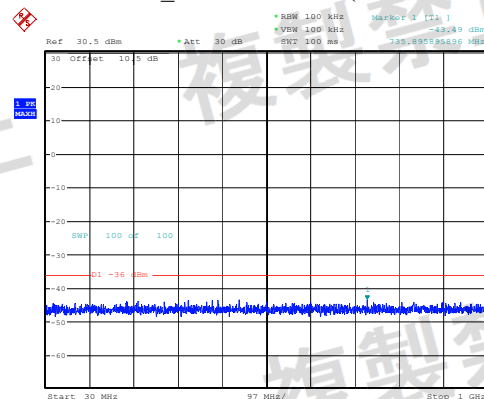
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:03:57

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:04:05

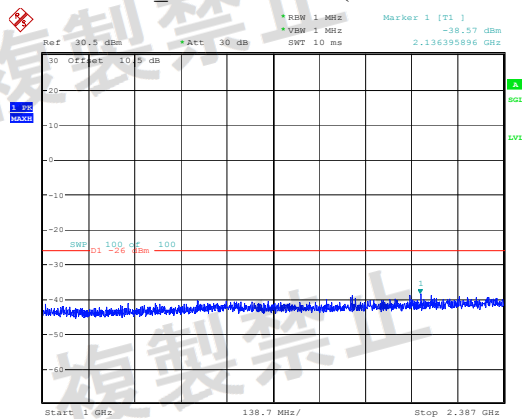
BLE 1M_Low Channel(2.4965GHz~12.5GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:04:30

BLE 1M_Middle Channel(30MHz~1GHz)

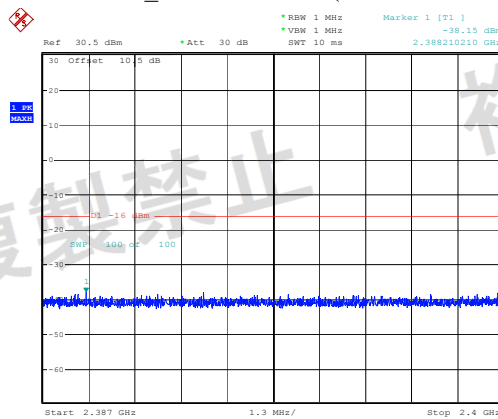
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BLE 1M_Middle Channel(1GHz~2.387GHz)



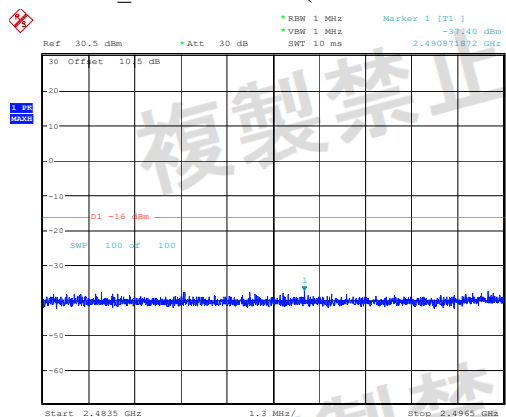
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Date: 4.JUL.2025 15:14:05

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



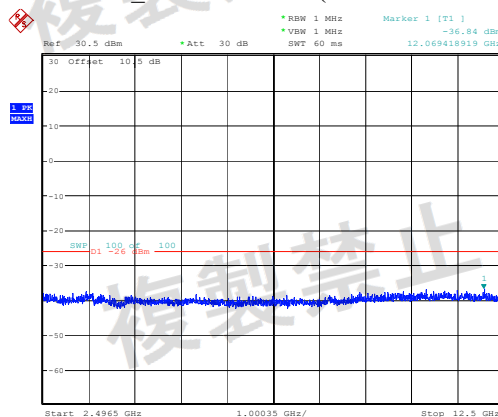
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Date: 4.JUL.2025 15:14:12

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



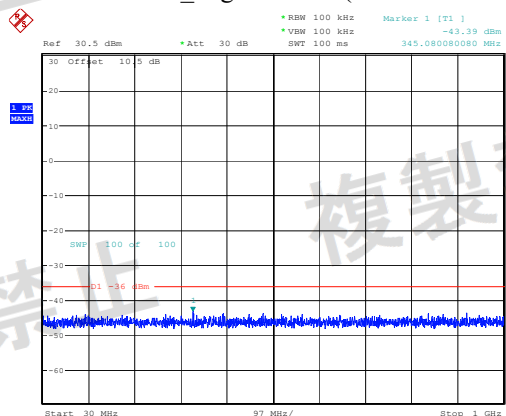
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Date: 4.JUL.2025 15:14:19

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



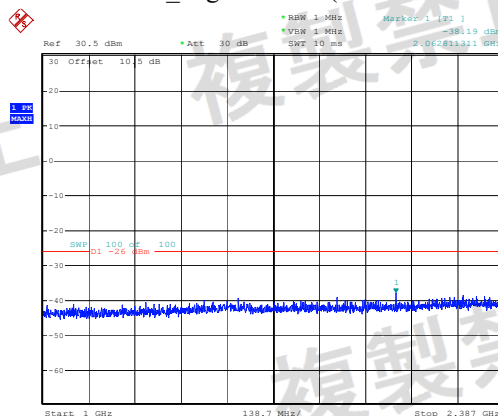
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:14:44

BLE 1M_High Channel(30MHz~1GHz)



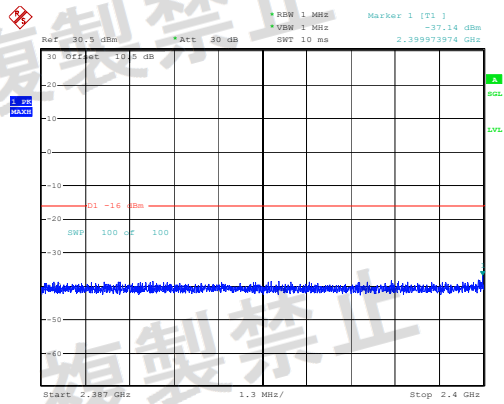
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:16:34

BLE 1M_High Channel(1GHz~2.387GHz)



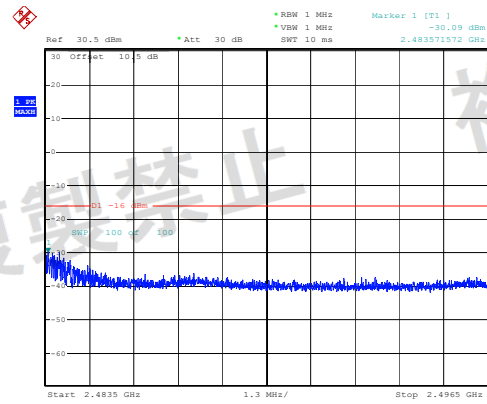
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Date: 4.JUL.2025 15:16:44

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:16:51

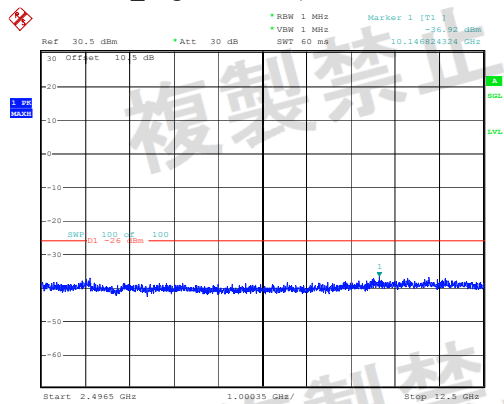
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:16:59

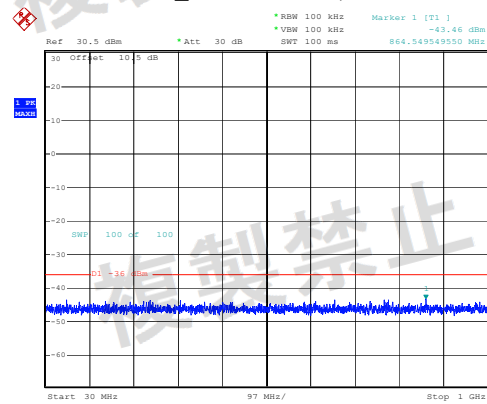
Test Condition: LV

BLE 1M_High Channel(2.4965GHz~12.5GHz)



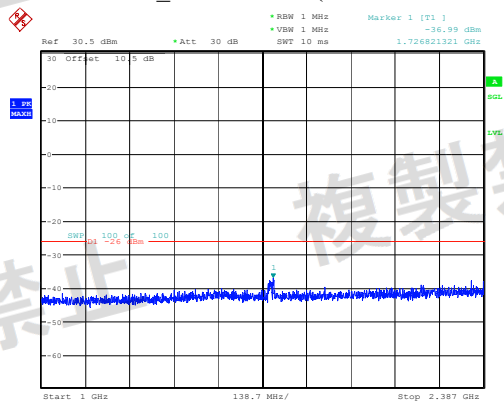
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Date: 4.JUL.2025 15:17:23

BLE 1M_Low Channel(30MHz~1GHz)



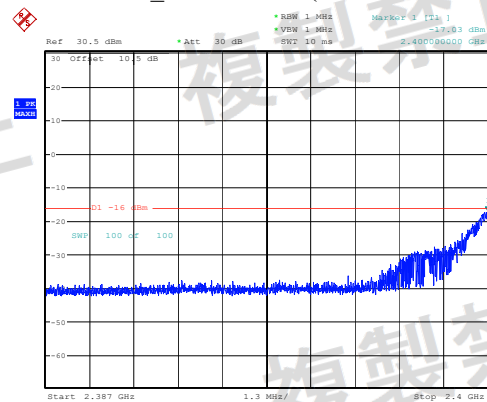
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Date: 4.JUL.2025 16:07:52

BLE 1M_Low Channel(1GHz~2.387GHz)



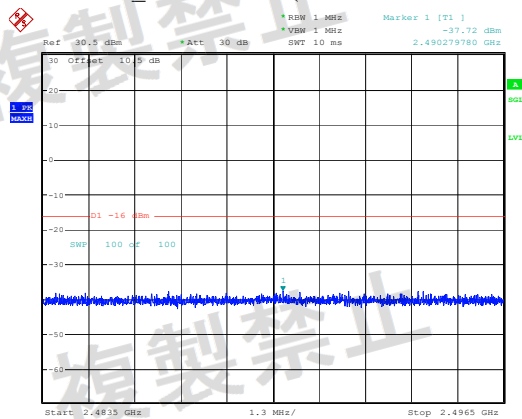
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Date: 4.JUL.2025 16:08:02

BLE 1M_Low Channel(2.387GHz~2.4GHz)



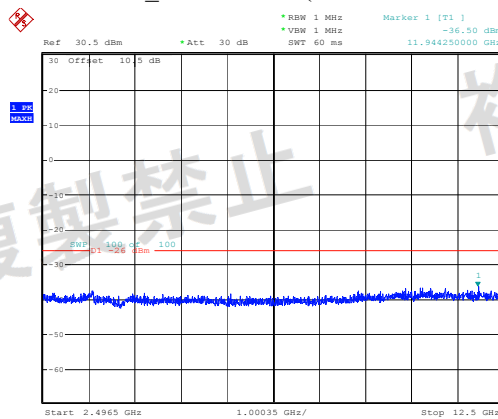
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:08:10

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)



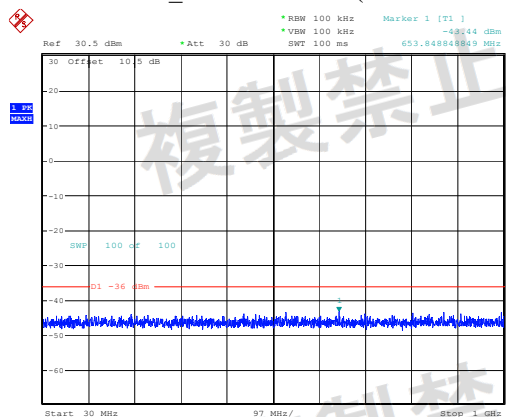
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Date: 4.JUL.2025 16:08:17

BLE 1M_Low Channel(2.4965GHz~12.5GHz)



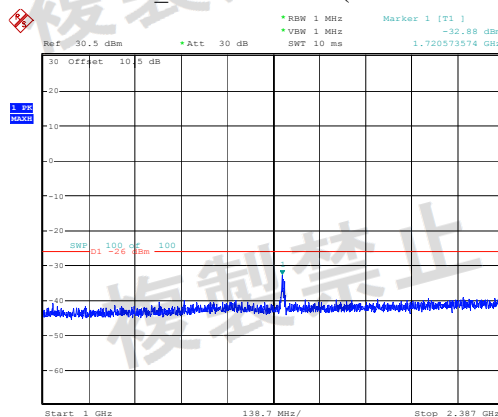
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:08:41

BLE 1M_Middle Channel(30MHz~1GHz)



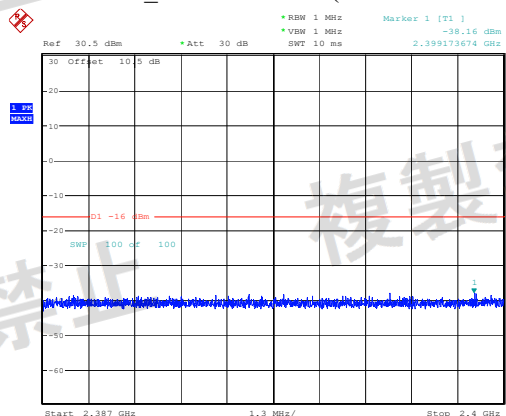
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:09:32

BLE 1M_Middle Channel(1GHz~2.387GHz)



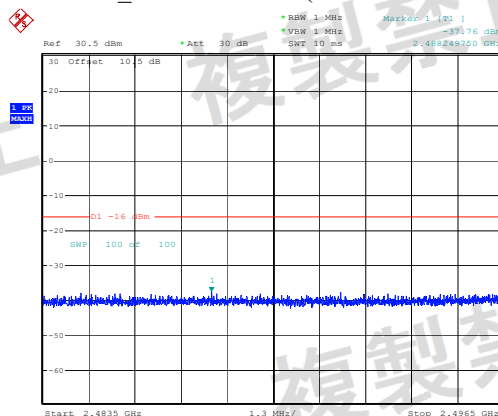
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Date: 4.JUL.2025 16:09:43

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



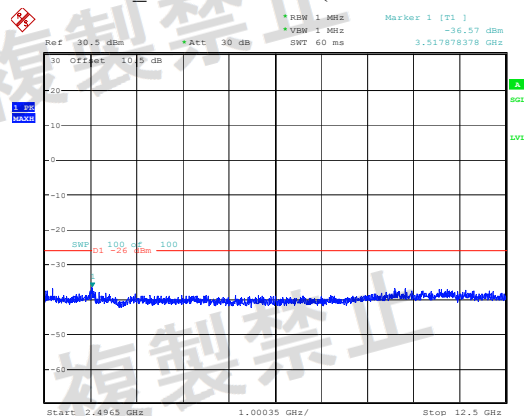
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:09:51

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



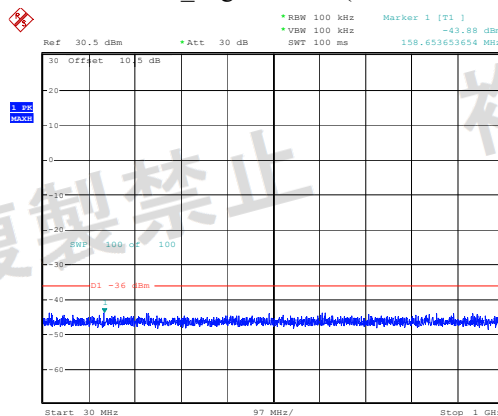
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:09:59

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



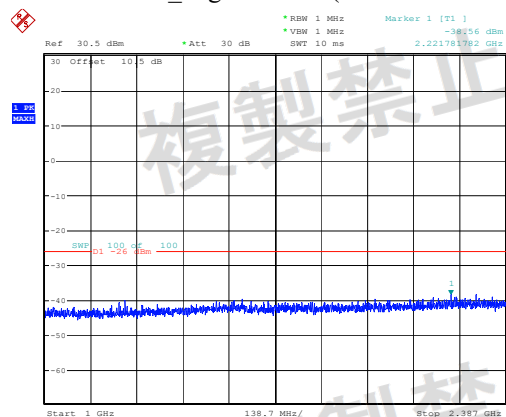
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:10:24

BLE 1M_High Channel(30MHz~1GHz)



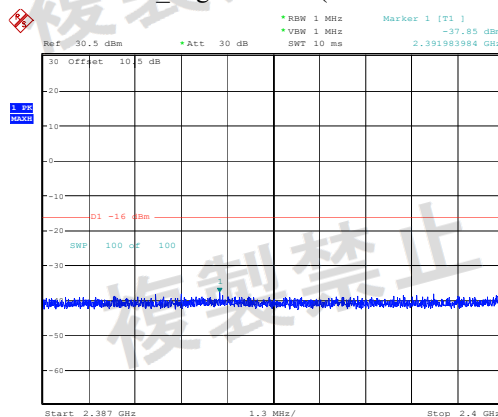
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:10:14

BLE 1M_High Channel(1GHz~2.387GHz)



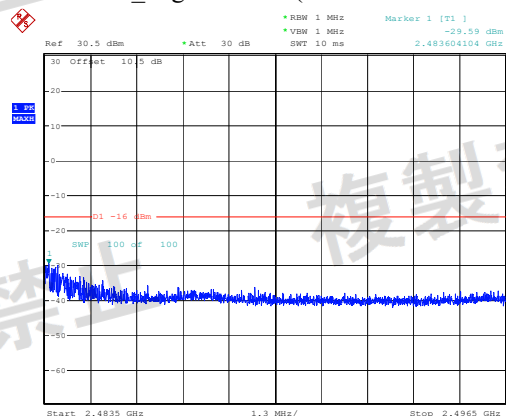
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Date: 4.JUL.2025 16:11:24

BLE 1M_High Channel(2.387GHz~2.4GHz)



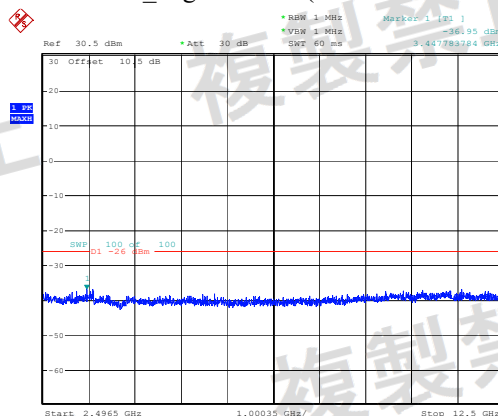
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Date: 4.JUL.2025 16:11:32

BLE 1M_High Channel(2.4835GHz~2.4965GHz)

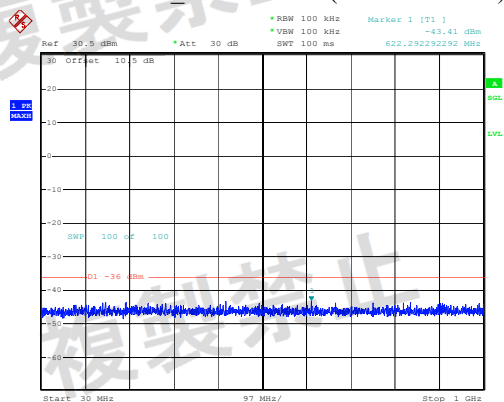


ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:11:42

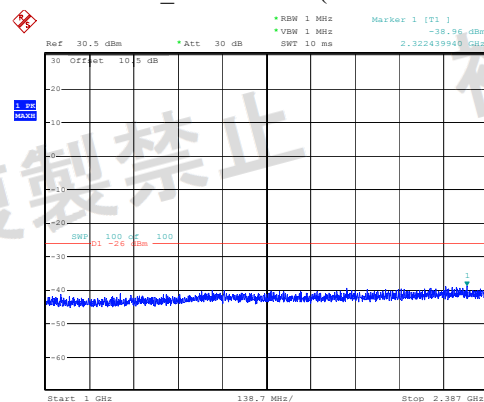
BLE 1M_High Channel(2.4965GHz~12.5GHz)



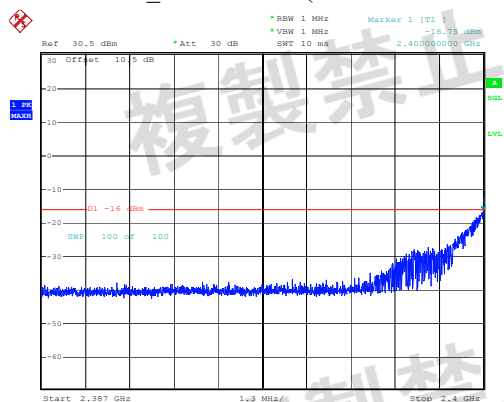
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Test Condition: HV**BLE 1M_Low Channel(30MHz~1GHz)**

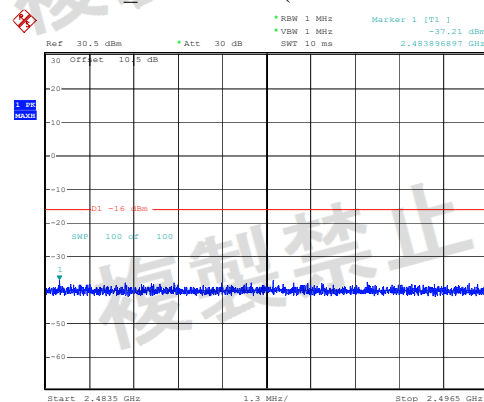
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:19:34

BLE 1M_Low Channel(1GHz~2.387GHz)

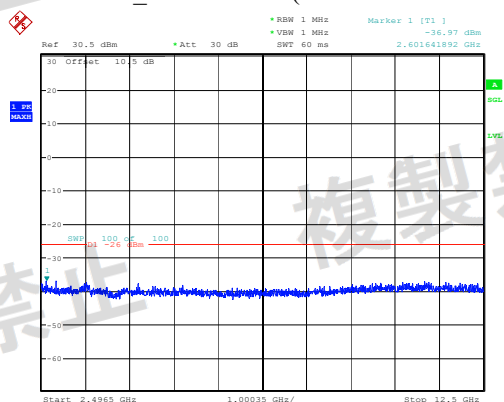
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BLE 1M_Low Channel(2.387GHz~2.4GHz)

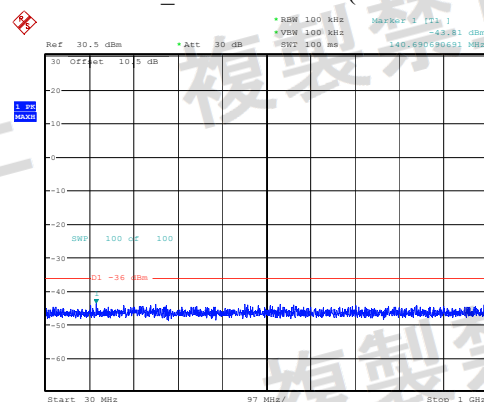
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Date: 4.JUL.2025 16:19:53

BLE 1M_Low Channel(2.4835GHz~2.4965GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:20:01

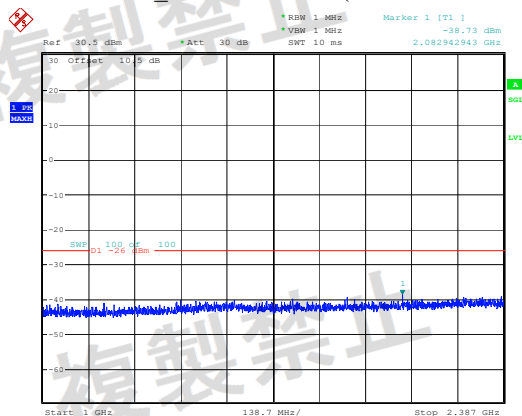
BLE 1M_Low Channel(2.4965GHz~12.5GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:20:27

BLE 1M_Middle Channel(30MHz~1GHz)

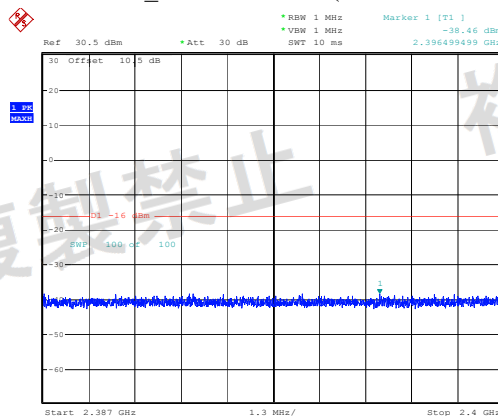
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:24:56

BLE 1M_Middle Channel(1GHz~2.387GHz)



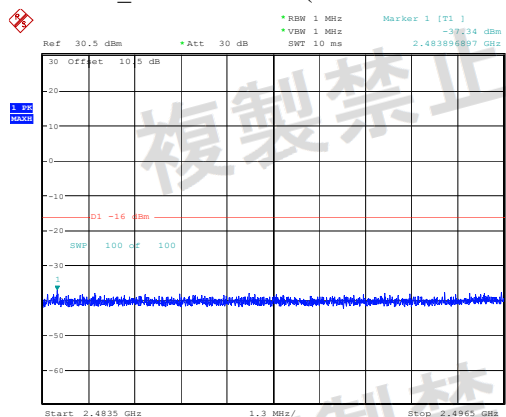
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:25:06

BLE 1M_Middle Channel(2.387GHz~2.4GHz)



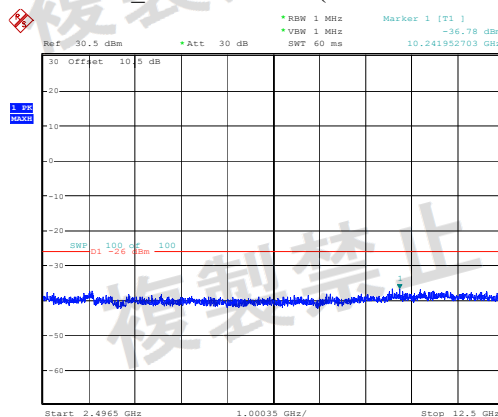
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:25:15

BLE 1M_Middle Channel(2.4835GHz~2.4965GHz)



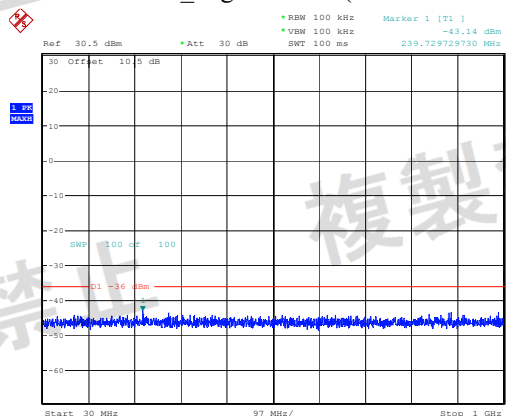
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:25:23

BLE 1M_Middle Channel(2.4965GHz~12.5GHz)



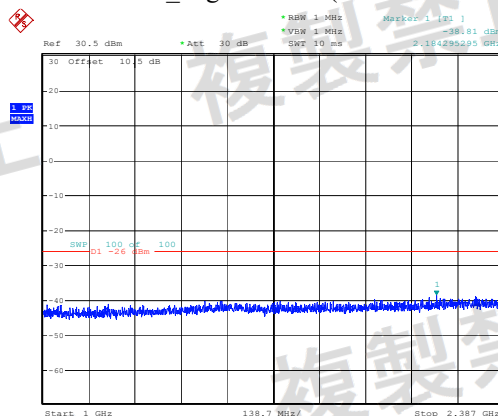
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:25:48

BLE 1M_High Channel(30MHz~1GHz)



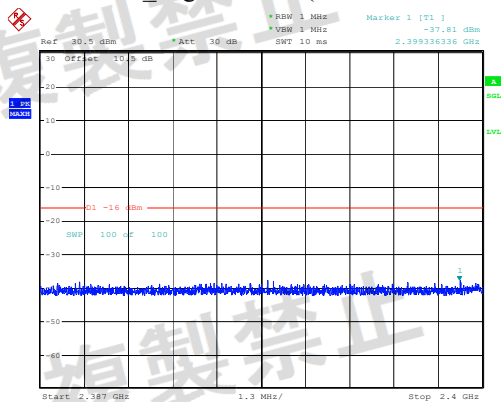
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:26:39

BLE 1M_High Channel(1GHz~2.387GHz)



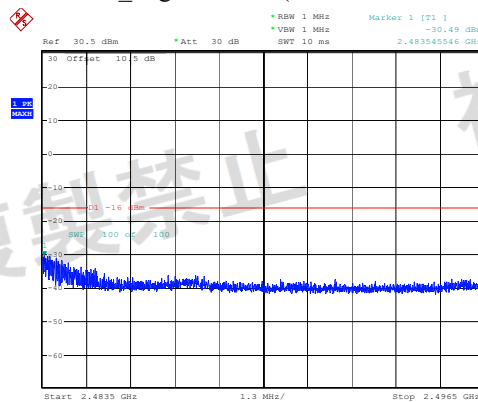
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:26:49

BLE 1M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:26:58

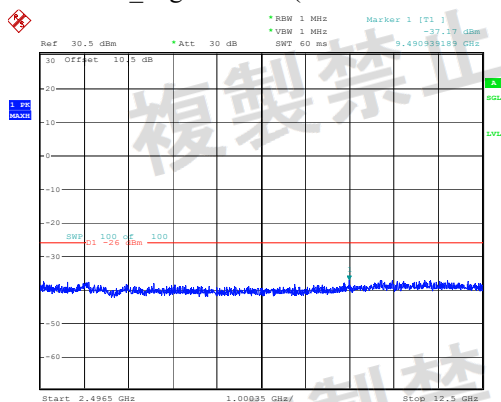
BLE 1M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:27:07

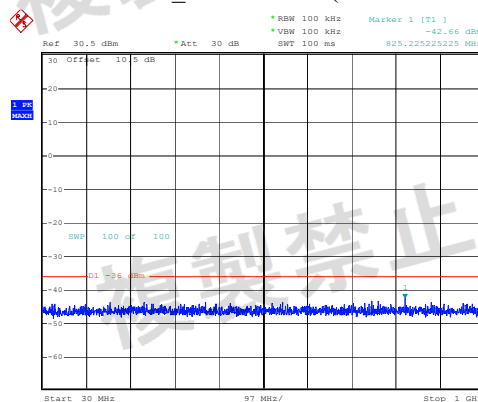
Test Condition: NV

BLE 1M_High Channel(2.4965GHz~12.5GHz)



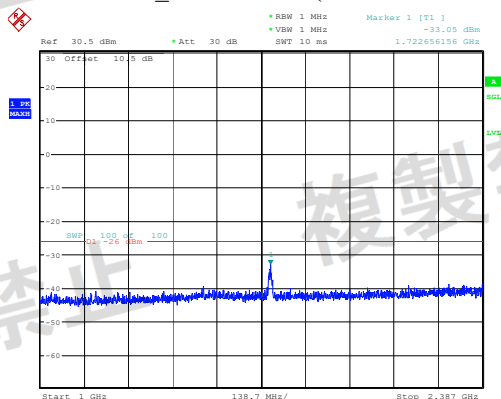
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:27:32

BLE 2M_Low Channel(30MHz~1GHz)



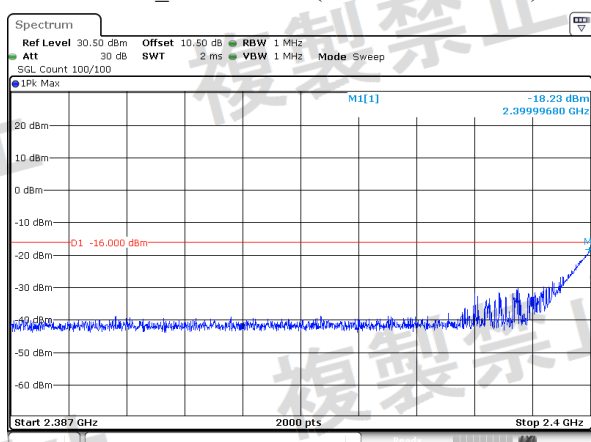
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:18:42

BLE 2M_Low Channel(1GHz~2.387GHz)



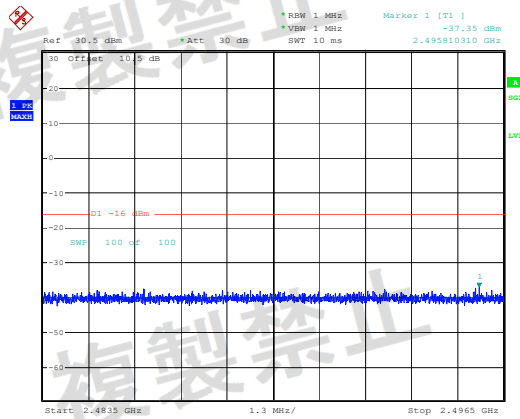
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:18:52

BLE 2M_Low Channel(2.387GHz~2.4GHz)



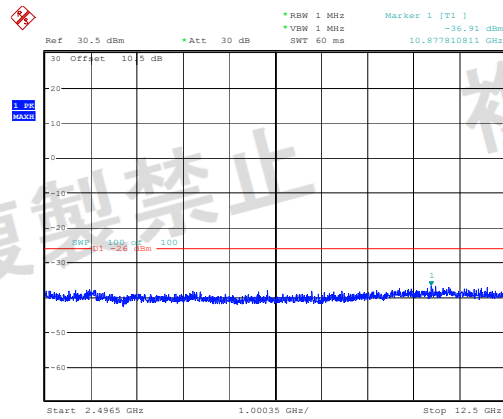
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 19:11:25

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



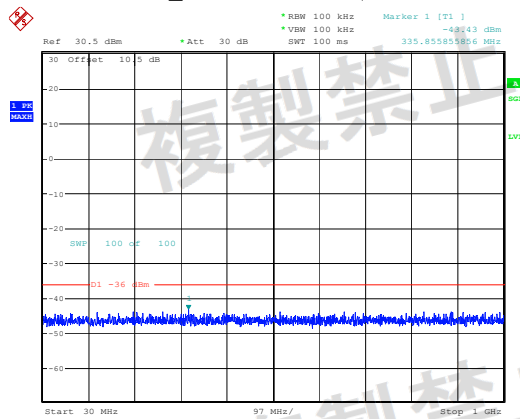
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:22:18

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



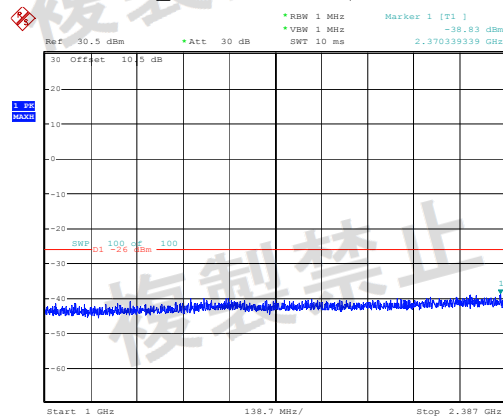
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:22:42

BLE 2M_Middle Channel(30MHz~1GHz)



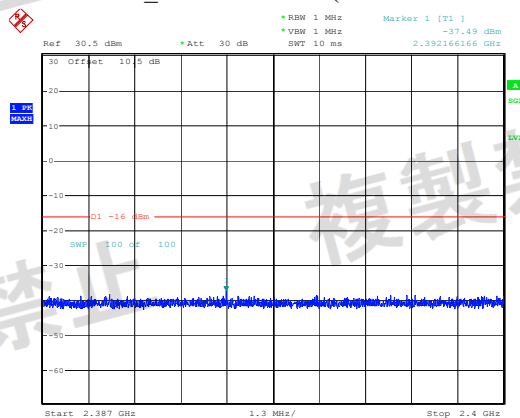
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:25:41

BLE 2M_Middle Channel(1GHz~2.387GHz)



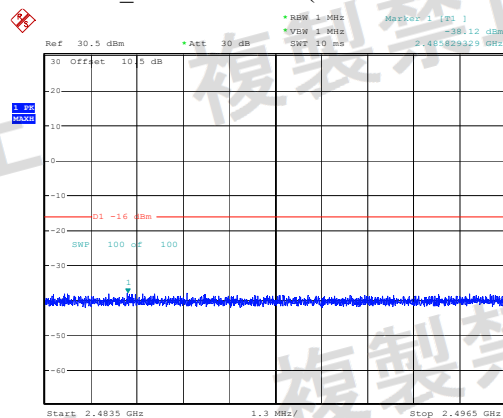
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:25:51

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



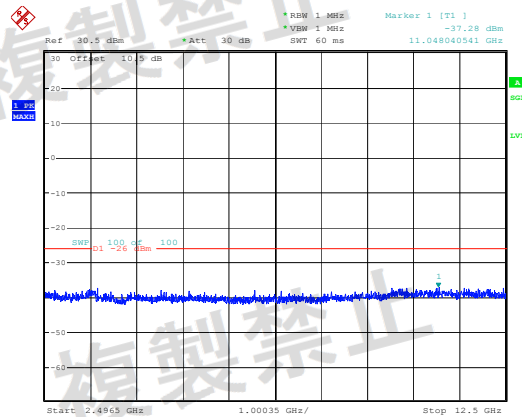
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:26:00

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



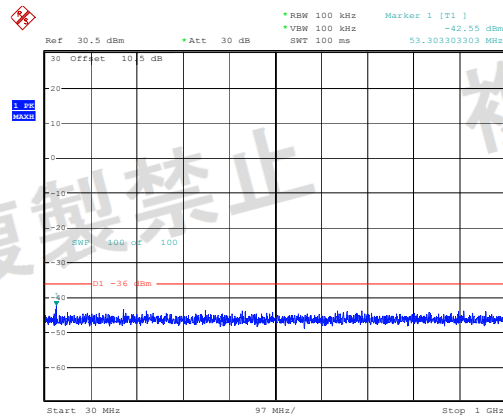
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:26:07

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



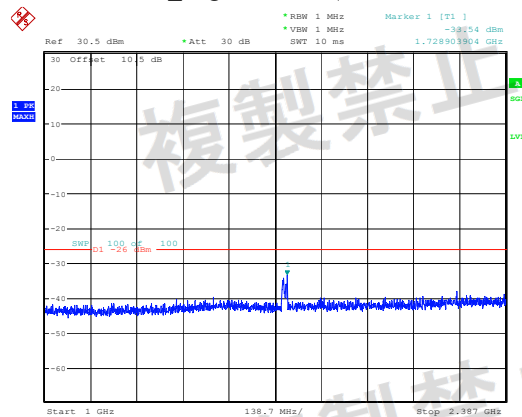
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:26:31

BLE 2M_High Channel(30MHz~1GHz)



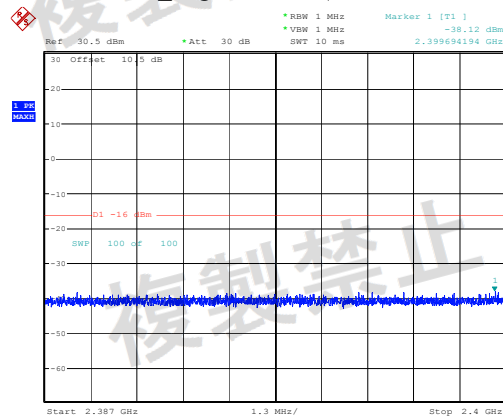
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:27:32

BLE 2M_High Channel(1GHz~2.387GHz)



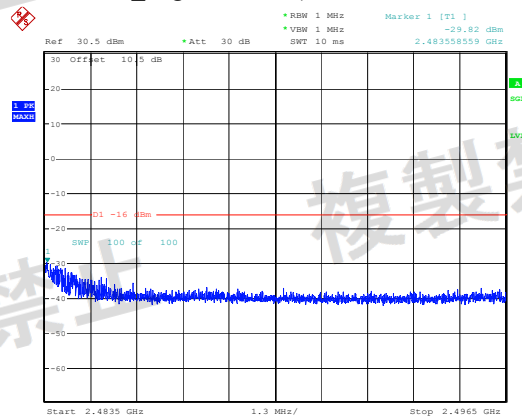
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:27:42

BLE 2M_High Channel(2.387GHz~2.4GHz)



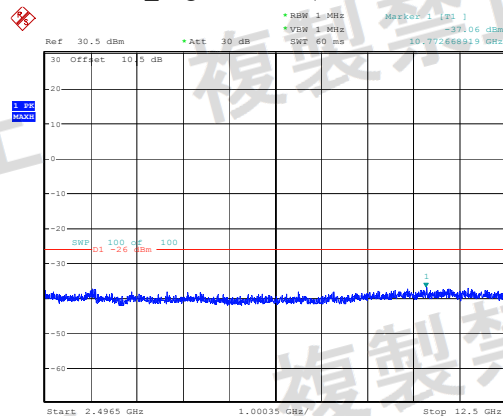
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:27:49

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:27:56

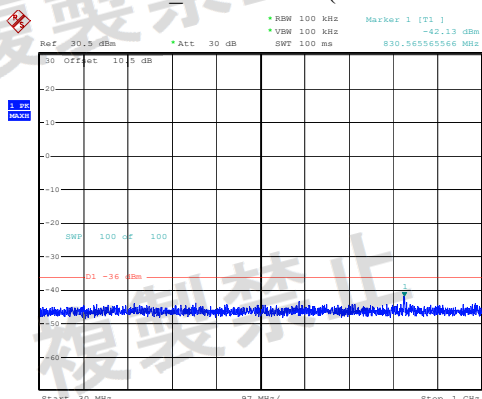
BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 15:28:21

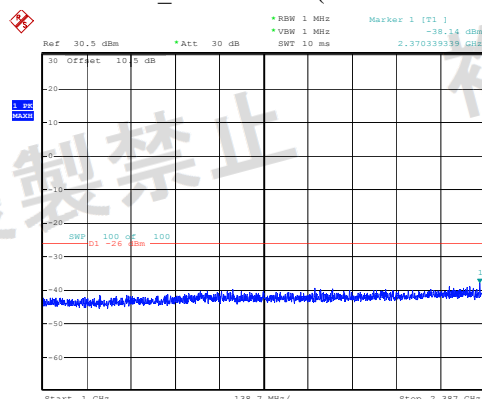
Test Condition: LV

BLE 2M_Low Channel(30MHz~1GHz)



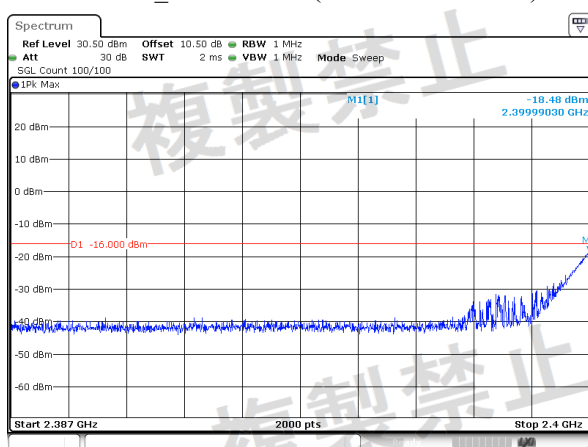
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:13:09

BLE 2M_Low Channel(1GHz~2.387GHz)



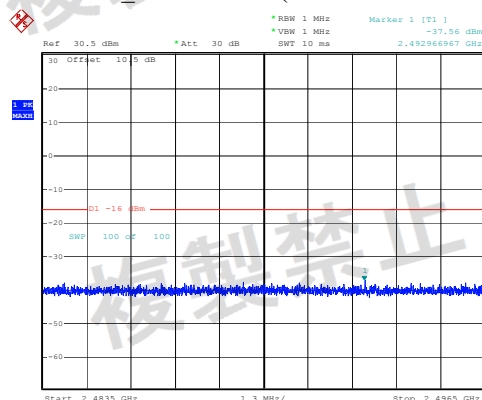
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:13:19

BLE 2M_Low Channel(2.387GHz~2.4GHz)



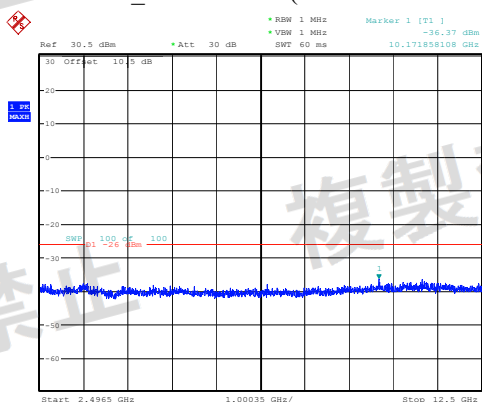
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 19:12:16

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



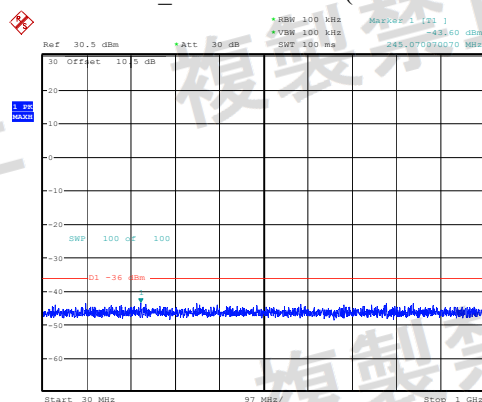
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:13:26

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



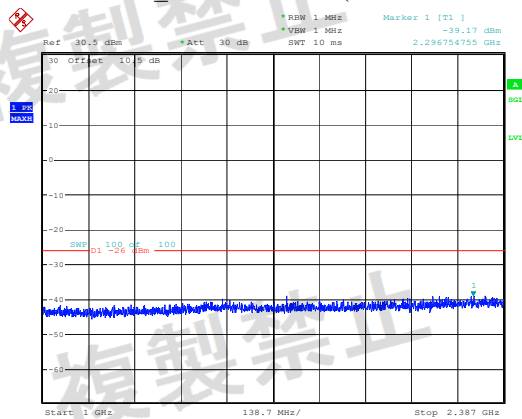
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:13:52

BLE 2M_Middle Channel(30MHz~1GHz)



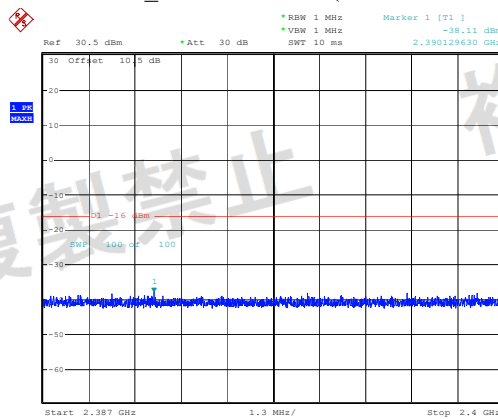
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:14:44

BLE 2M_Middle Channel(1GHz~2.387GHz)



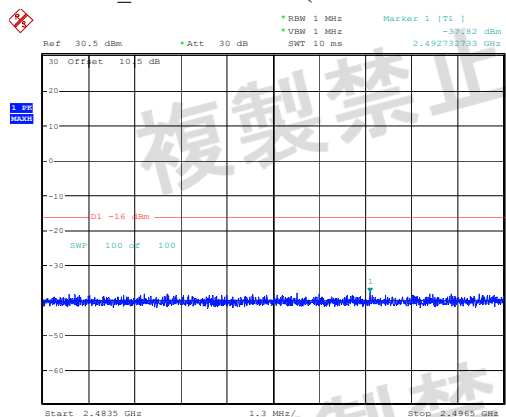
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:14:55

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



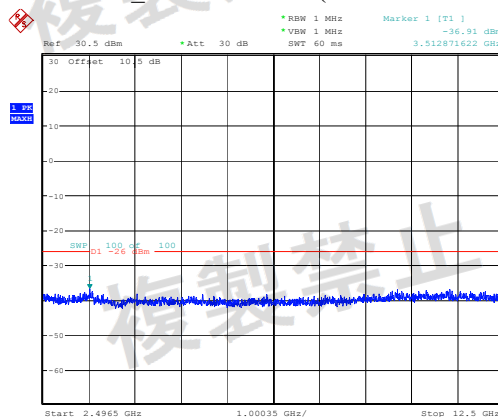
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:15:04

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



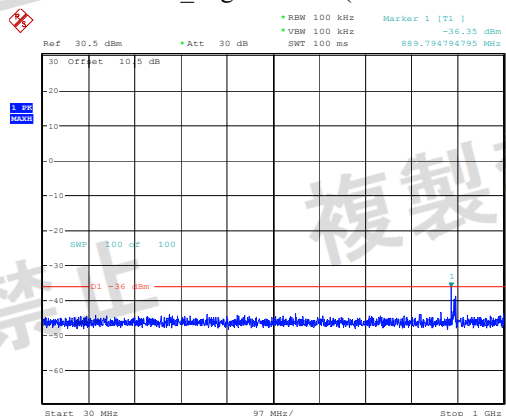
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:15:12

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



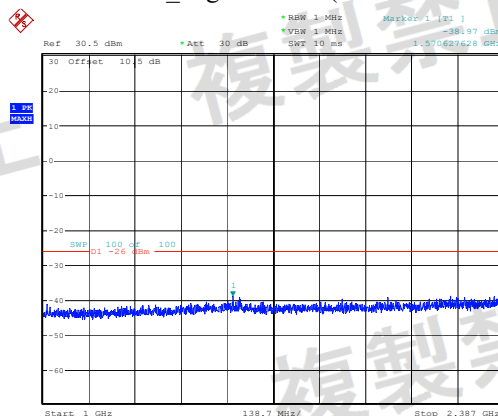
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:15:39

BLE 2M_High Channel(30MHz~1GHz)



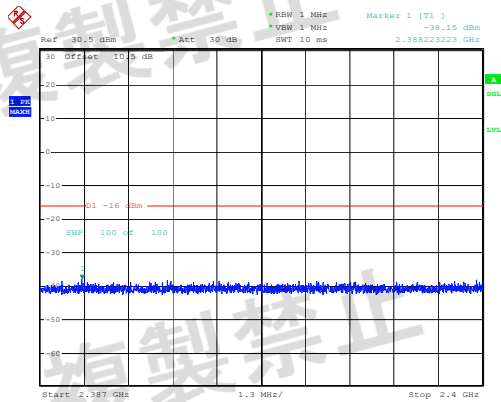
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:16:21

BLE 2M_High Channel(1GHz~2.387GHz)



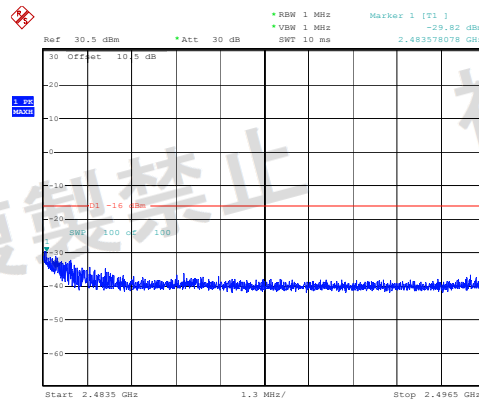
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:16:32

BLE 2M_High Channel(2.387GHz~2.4GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:16:40

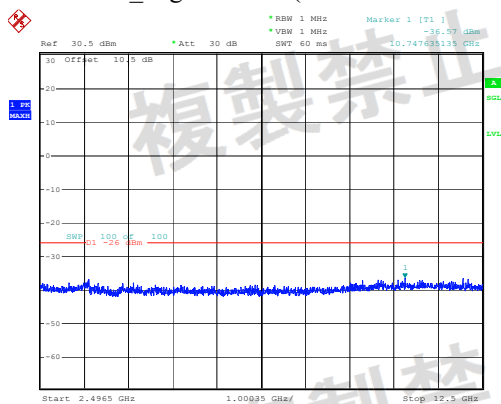
BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:16:48

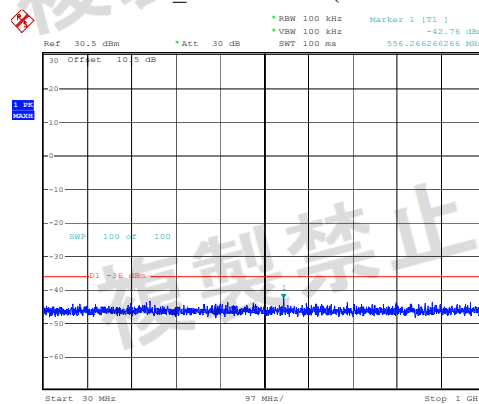
Test Condition: HV

BLE 2M_High Channel(2.4965GHz~12.5GHz)



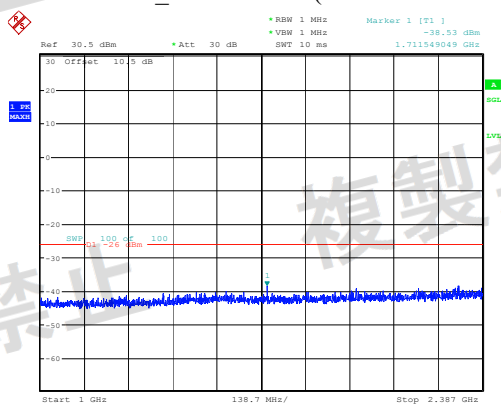
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:17:13

BLE 2M_Low Channel(30MHz~1GHz)



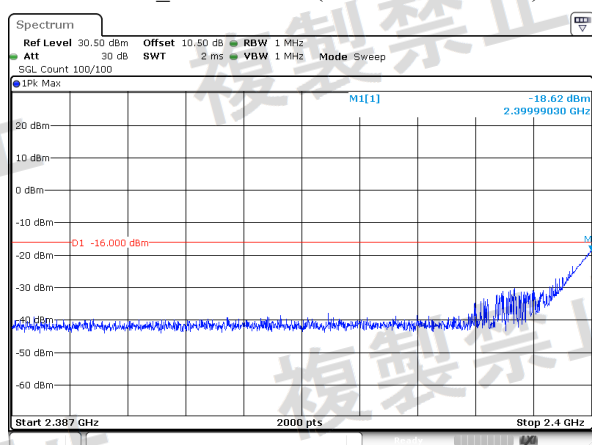
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:28:25

BLE 2M_Low Channel(1GHz~2.387GHz)



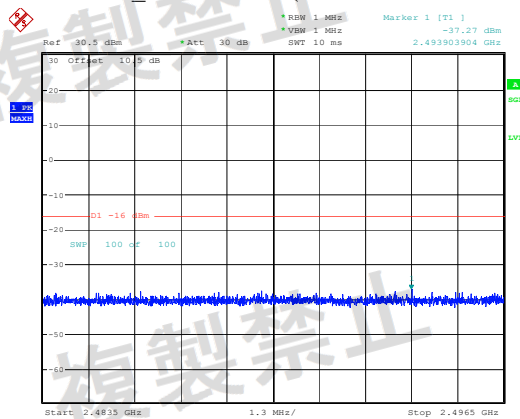
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:28:36

BLE 2M_Low Channel(2.387GHz~2.4GHz)



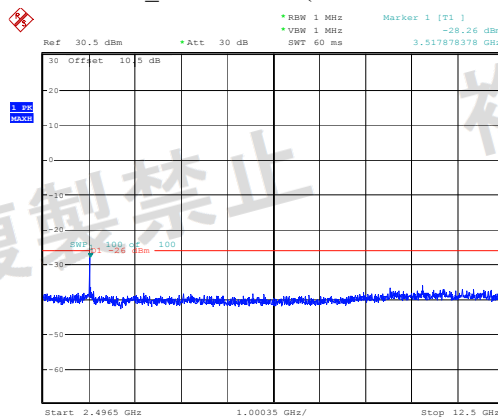
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 19:12:42

BLE 2M_Low Channel(2.4835GHz~2.4965GHz)



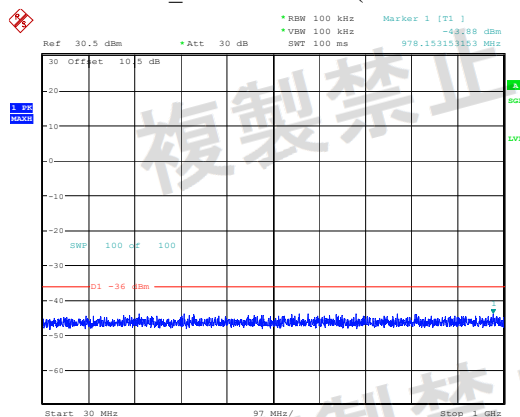
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:29:32

BLE 2M_Low Channel(2.4965GHz~12.5GHz)



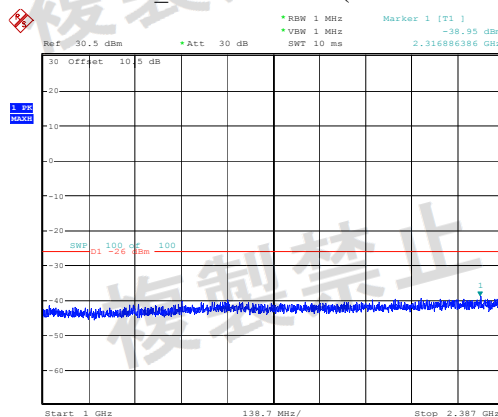
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:29:58

BLE 2M_Middle Channel(30MHz~1GHz)



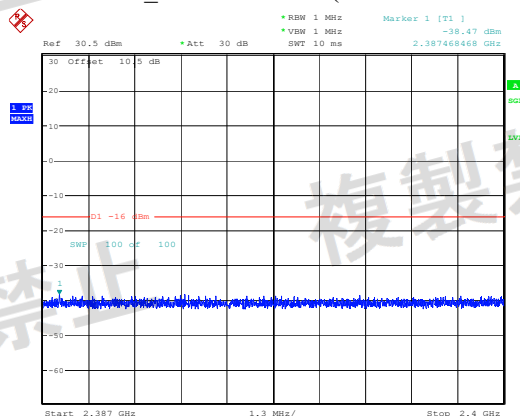
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:30:51

BLE 2M_Middle Channel(1GHz~2.387GHz)



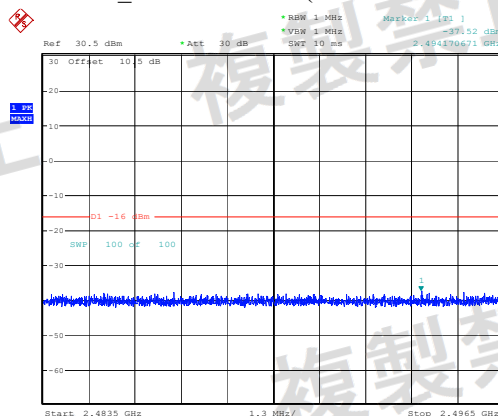
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:31:01

BLE 2M_Middle Channel(2.387GHz~2.4GHz)



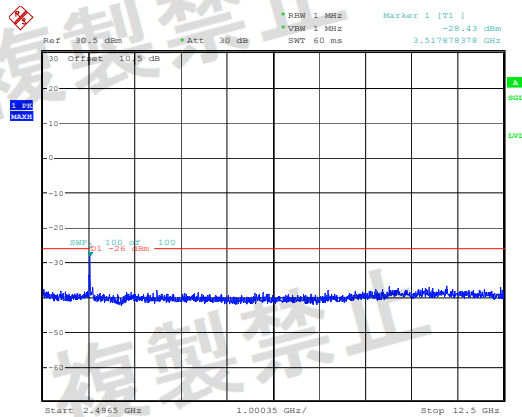
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:31:10

BLE 2M_Middle Channel(2.4835GHz~2.4965GHz)



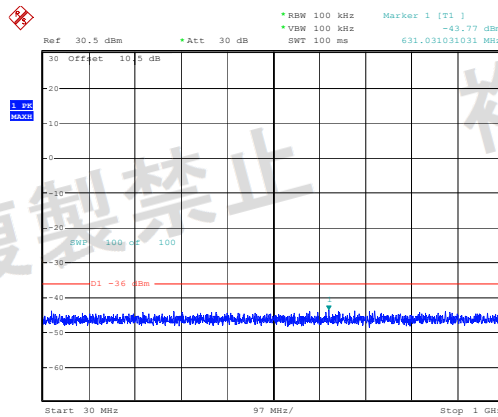
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:31:18

BLE 2M_Middle Channel(2.4965GHz~12.5GHz)



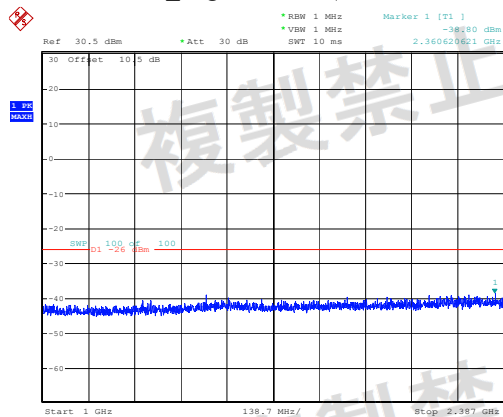
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:31:43

BLE 2M_High Channel(30MHz~1GHz)



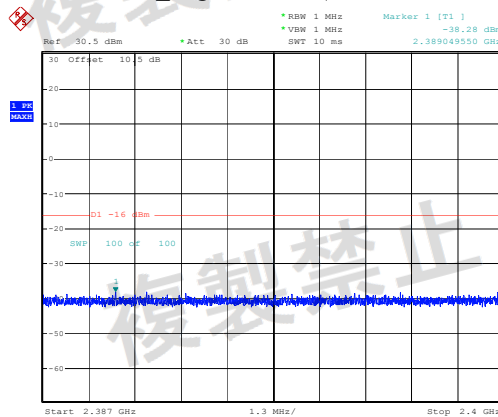
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:32:82

BLE 2M_High Channel(1GHz~2.387GHz)



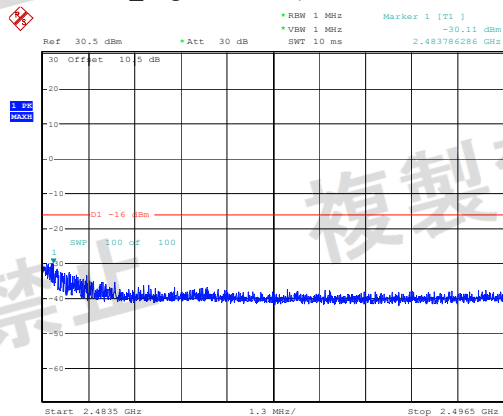
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:32:44

BLE 2M_High Channel(2.387GHz~2.4GHz)



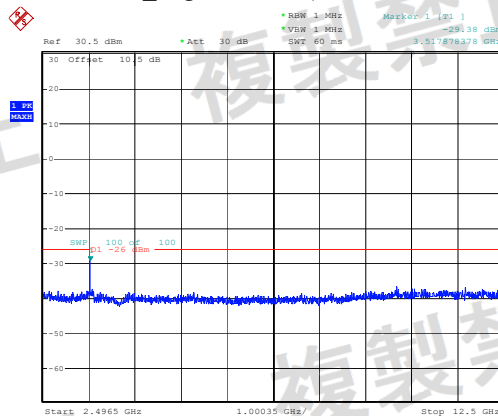
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:32:52

BLE 2M_High Channel(2.4835GHz~2.4965GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:33:01

BLE 2M_High Channel(2.4965GHz~12.5GHz)



ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 16:33:26

Antenna Output Power and Output Power Tolerance**Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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Test Condition: NV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	-6.34	3.00
BLE 2M		3.00

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	4.60	2.884	≤ 10	-3.87	-80~+20	-1.74	≤ 12.14	Pass
	Middle	4.92	3.105		3.50		-1.42		Pass
	High	4.83	3.041		1.37		-1.51		Pass
BLE 2M	Low	4.32	2.704	≤ 10	-9.87	-80~+20	-2.02	≤ 12.14	Pass
	Middle	4.68	2.938		-2.07		-1.66		Pass
	High	4.43	2.773		-7.57		-1.91		Pass

Test Condition: LV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	-6.34	3.00
BLE 2M		3.00

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	4.58	2.871	≤ 10	-4.30	-80~+20	-1.76	≤ 12.14	Pass
	Middle	4.87	3.069		2.30		-1.47		Pass
	High	4.69	2.944		-1.87		-1.65		Pass
BLE 2M	Low	4.25	2.661	≤ 10	-11.30	-80~+20	-2.09	≤ 12.14	Pass
	Middle	4.52	2.831		-5.63		-1.82		Pass
	High	4.61	2.891		-3.63		-1.73		Pass

Test Condition: HV

Mode	Antenna gain (dBi)	Declared power (mW)
BLE 1M	-6.34	3.00
BLE 2M		3.00

Mode	Channel	Conducted power(dBm)	Antenna output power(mW)		Antenna output tolerance(%)		EIRP (dBm)		Verdict
			Result	Limit	Result	Limit	Result	Limit	
BLE 1M	Low	4.47	2.799	≤ 10	-6.70	-80~+20	-1.87	≤ 12.14	Pass
	Middle	4.89	3.083		2.77		-1.45		Pass
	High	4.73	2.972		-0.93		-1.61		Pass
BLE 2M	Low	4.29	2.685	≤ 10	-10.50	-80~+20	-2.05	≤ 12.14	Pass
	Middle	4.58	2.871		-4.30		-1.76		Pass
	High	4.44	2.780		-7.33		-1.90		Pass

Note:

Antenna output power(mW) = $10^{\{\text{Conducted power(dBm)} / 10\}}$

Antenna output power tolerance(%) = (Antenna output power - Declared power) / Declared power * 100%

EIRP(dBm) = Conducted power(dBm) + Antenna gain.

Receiver Spurious Emission and Unwanted Emission Intensity**Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Transmitting
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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Test Condition: NV

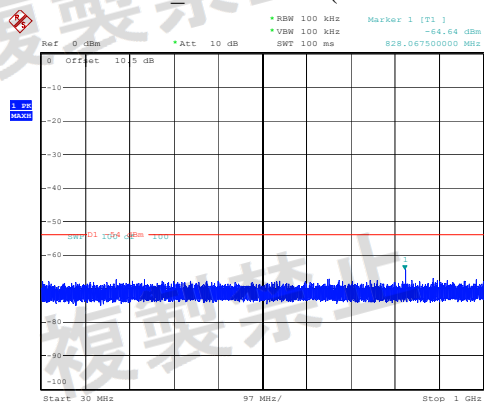
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	828.0675	-64.64	0.344	4	Pass
		Band II (1MHz)	1000	12500	10107.425	-57.95	1.603	20	Pass
	Middle	Band I (100kHz)	30	1000	740.1855	-67.31	0.186	4	Pass
		Band II (1MHz)	1000	12500	10745.675	-58.25	1.496	20	Pass
	High	Band I (100kHz)	30	1000	460.3405	-67.14	0.193	4	Pass
		Band II (1MHz)	1000	12500	10881.375	-57.07	1.963	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	973.9555	-67.13	0.194	4	Pass
		Band II (1MHz)	1000	12500	10063.725	-57.53	1.766	20	Pass
	Middle	Band I (100kHz)	30	1000	738.6335	-67.09	0.195	4	Pass
		Band II (1MHz)	1000	12500	10456.45	-58.12	1.542	20	Pass
	High	Band I (100kHz)	30	1000	888.547	-67.15	0.193	4	Pass
		Band II (1MHz)	1000	12500	12307.375	-57.93	1.611	20	Pass

Test Condition: LV

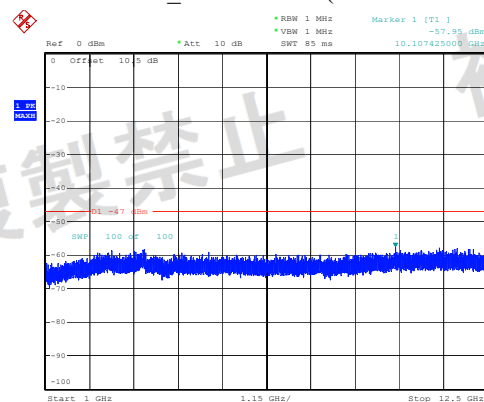
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	169.3405	-67.17	0.192	4	Pass
		Band II (1MHz)	1000	12500	11335.625	-58.09	1.552	20	Pass
	Middle	Band I (100kHz)	30	1000	379.976	-66.97	0.201	4	Pass
		Band II (1MHz)	1000	12500	11824.375	-57.69	1.702	20	Pass
	High	Band I (100kHz)	30	1000	925.019	-67.19	0.191	4	Pass
		Band II (1MHz)	1000	12500	11218.325	-57.90	1.622	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	745.8115	-66.48	0.225	4	Pass
		Band II (1MHz)	1000	12500	11240.75	-57.84	1.644	20	Pass
	Middle	Band I (100kHz)	30	1000	776.7545	-66.80	0.209	4	Pass
		Band II (1MHz)	1000	12500	9657.775	-58.23	1.503	20	Pass
	High	Band I (100kHz)	30	1000	209.45	-66.96	0.201	4	Pass
		Band II (1MHz)	1000	12500	10158.025	-57.27	1.875	20	Pass

Test Condition: HV

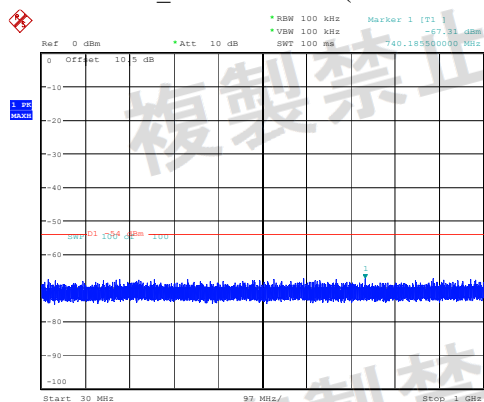
Mode	Channel	Test Band (RBW)	Frequency Range		Max.Emission Located(MHz)	Result (dBm)	Result (nW)	Limit (nW)	Verdict
			Start (MHz)	Stop (MHz)					
BLE 1M	Low	Band I (100kHz)	30	1000	801.1985	-67.44	0.180	4	Pass
		Band II (1MHz)	1000	12500	11194.175	-57.89	1.626	20	Pass
	Middle	Band I (100kHz)	30	1000	270.9965	-67.21	0.190	4	Pass
		Band II (1MHz)	1000	12500	10315.575	-57.83	1.648	20	Pass
	High	Band I (100kHz)	30	1000	381.334	-66.58	0.220	4	Pass
		Band II (1MHz)	1000	12500	10184.475	-57.77	1.671	20	Pass
BLE 2M	Low	Band I (100kHz)	30	1000	552.5875	-67.18	0.191	4	Pass
		Band II (1MHz)	1000	12500	10152.275	-57.81	1.656	20	Pass
	Middle	Band I (100kHz)	30	1000	297.0895	-66.42	0.228	4	Pass
		Band II (1MHz)	1000	12500	3581.175	-57.42	1.811	20	Pass
	High	Band I (100kHz)	30	1000	573.103	-66.35	0.232	4	Pass
		Band II (1MHz)	1000	12500	3313.225	-58.12	1.542	20	Pass

Test Condition: NV**BLE 1M_Low Channel(30MHz~1GHz)**

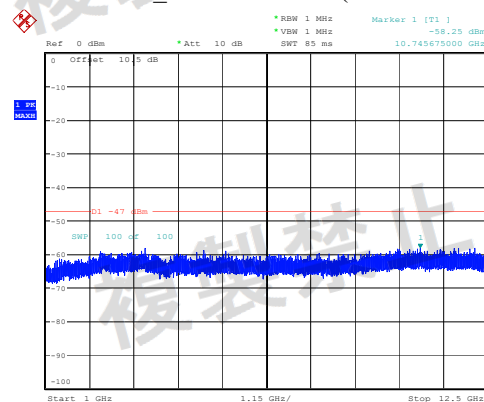
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:18:26

BLE 1M_Low Channel(1GHz~12.5GHz)

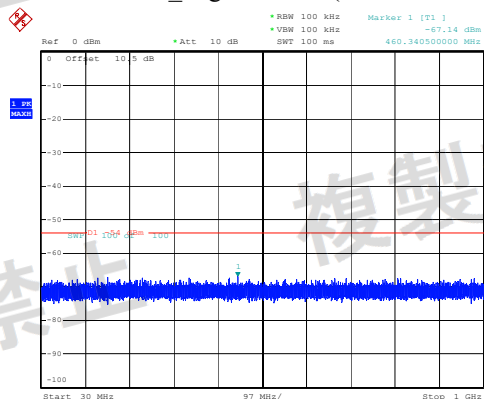
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:33:45

BLE 1M_Middle Channel(30MHz~1GHz)

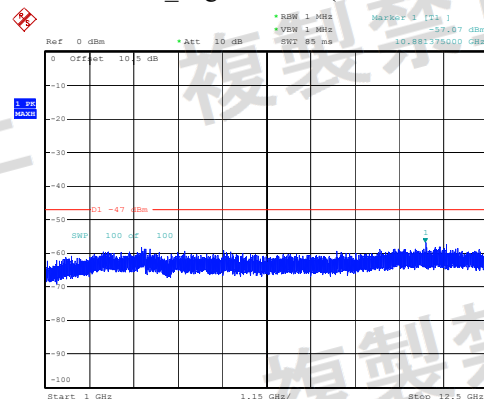
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:19:21

BLE 1M_Middle Channel(1GHz~12.5GHz)

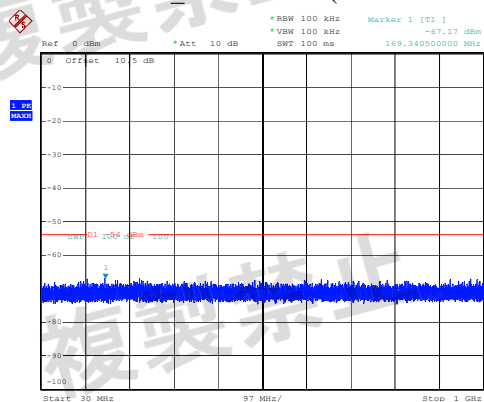
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:34:21

BLE 1M_High Channel(30MHz~1GHz)

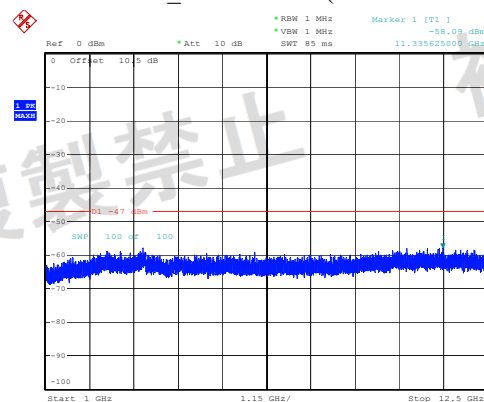
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:34:43

BLE 1M_High Channel(1GHz~12.5GHz)

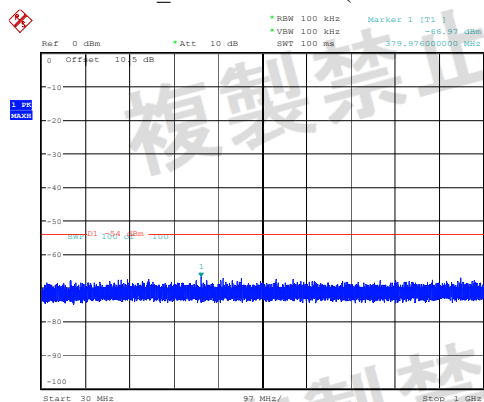
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:35:15

Test Condition: LV**BLE 1M_Low Channel(30MHz~1GHz)**

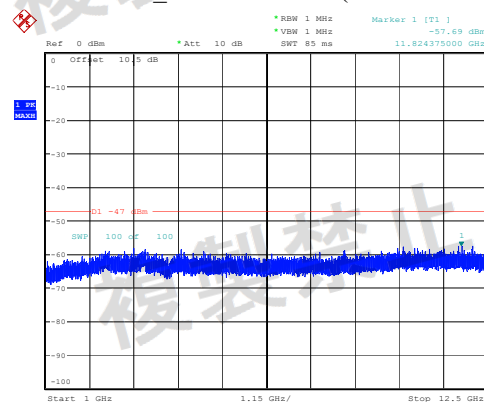
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:41:43

BLE 1M_Low Channel(1GHz~12.5GHz)

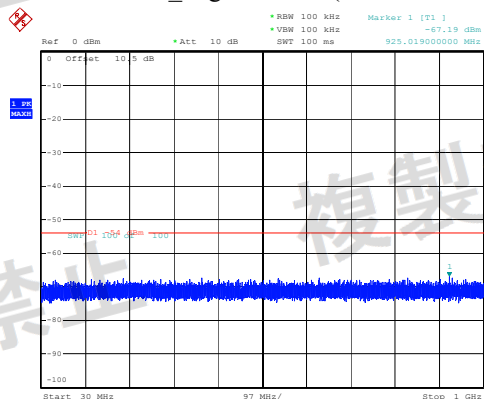
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:42:14

BLE 1M_Middle Channel(30MHz~1GHz)

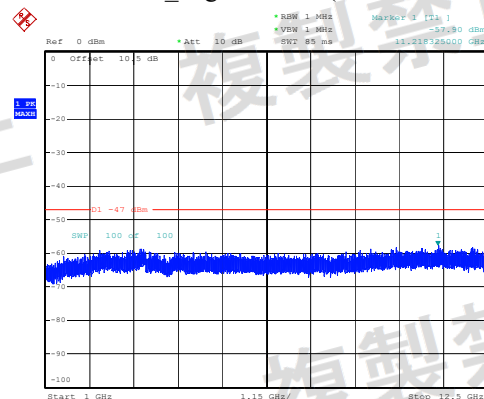
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:42:43

BLE 1M_Middle Channel(1GHz~12.5GHz)

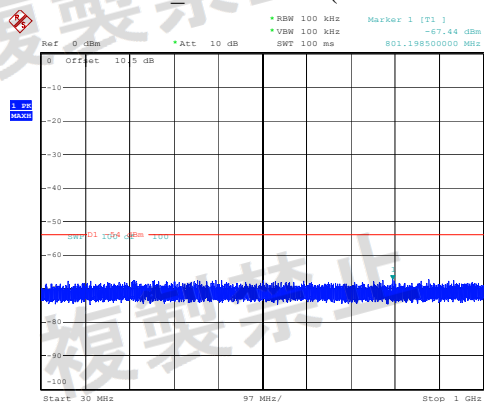
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:43:14

BLE 1M_High Channel(30MHz~1GHz)

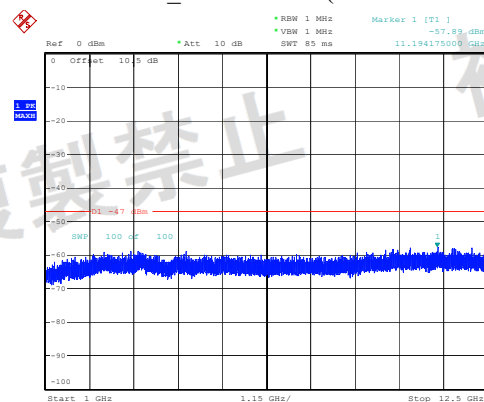
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:43:36

BLE 1M_High Channel(1GHz~12.5GHz)

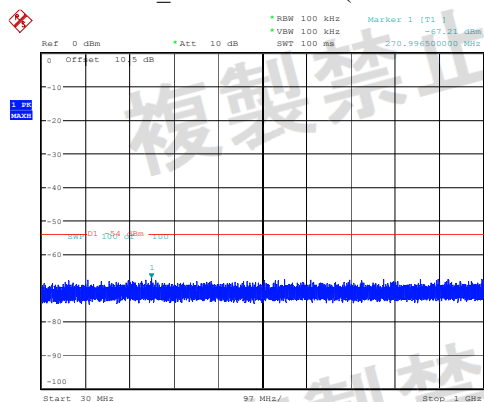
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:44:07

Test Condition: HV**BLE 1M_Low Channel(30MHz~1GHz)**

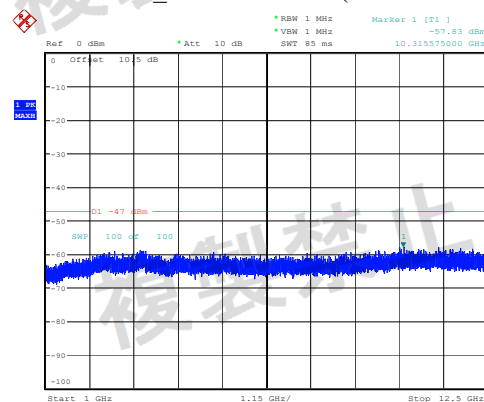
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:47:37

BLE 1M_Low Channel(1GHz~12.5GHz)

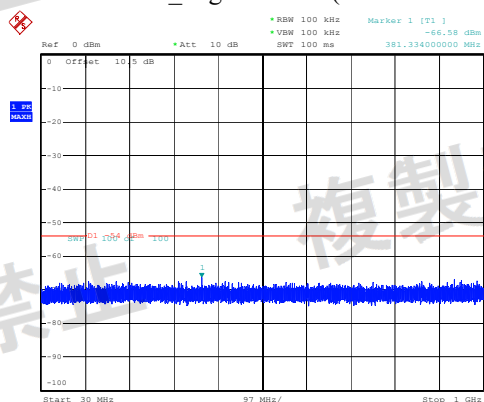
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:48:08

BLE 1M_Middle Channel(30MHz~1GHz)

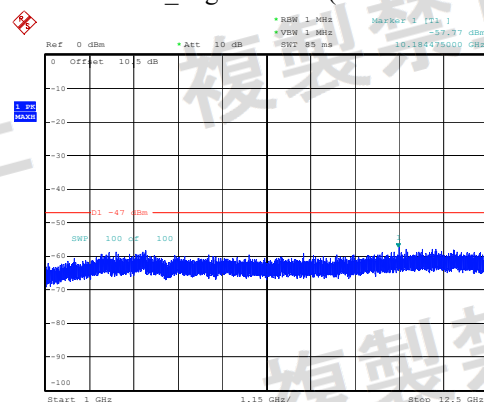
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:48:31

BLE 1M_Middle Channel(1GHz~12.5GHz)

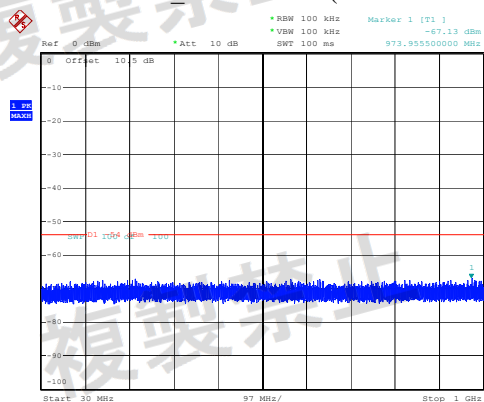
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:49:03

BLE 1M_High Channel(30MHz~1GHz)

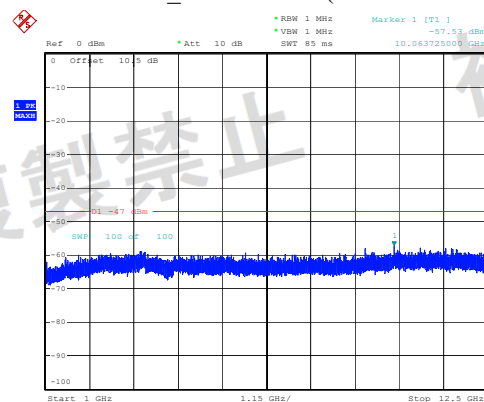
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:49:28

BLE 1M_High Channel(1GHz~12.5GHz)

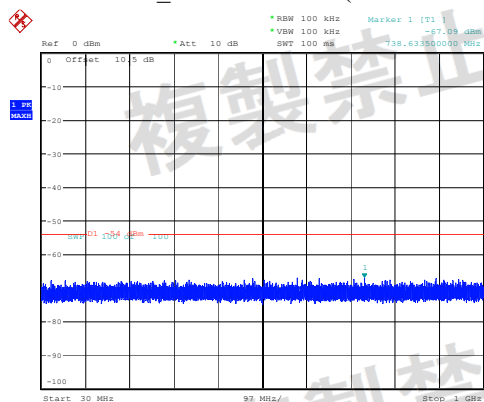
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:50:00

Test Condition: NV**BLE 2M_Low Channel(30MHz~1GHz)**

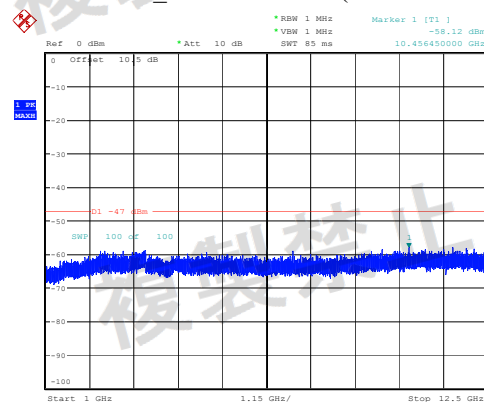
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:35:38

BLE 2M_Low Channel(1GHz~12.5GHz)

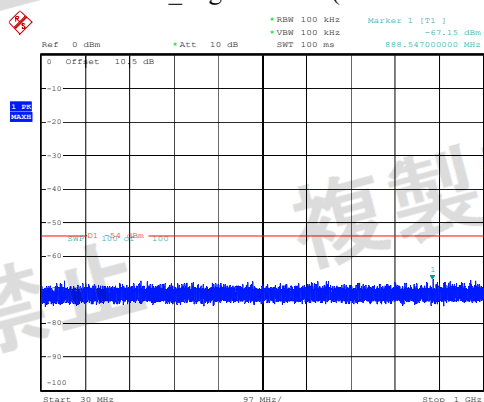
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:36:09

BLE 2M_Middle Channel(30MHz~1GHz)

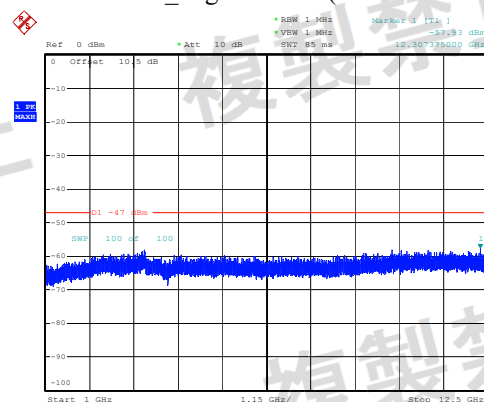
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:36:31

BLE 2M_Middle Channel(1GHz~12.5GHz)

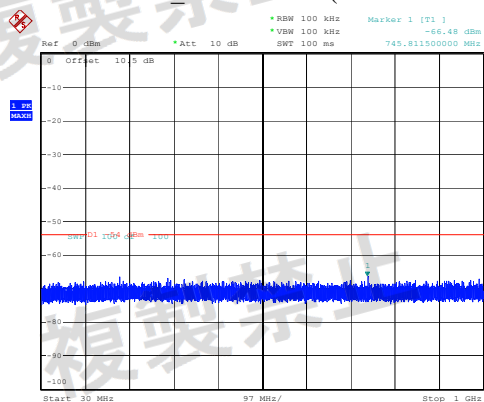
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:37:03

BLE 2M_High Channel(30MHz~1GHz)

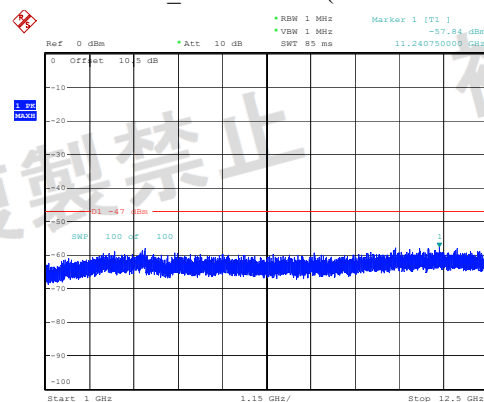
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:37:25

BLE 2M_High Channel(1GHz~12.5GHz)

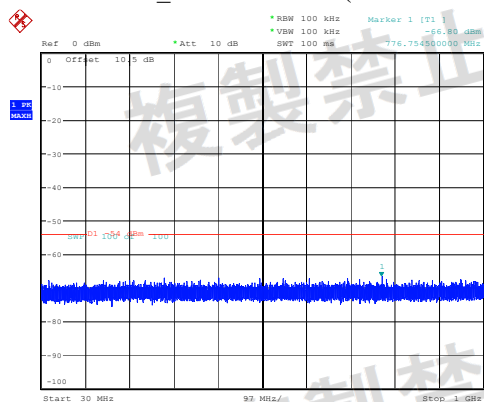
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:37:56

Test Condition: LV**BLE 2M_Low Channel(30MHz~1GHz)**

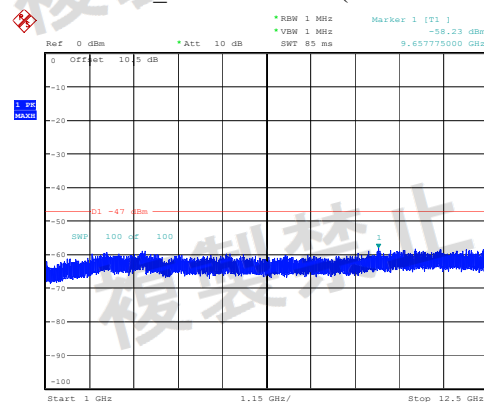
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:44:29

BLE 2M_Low Channel(1GHz~12.5GHz)

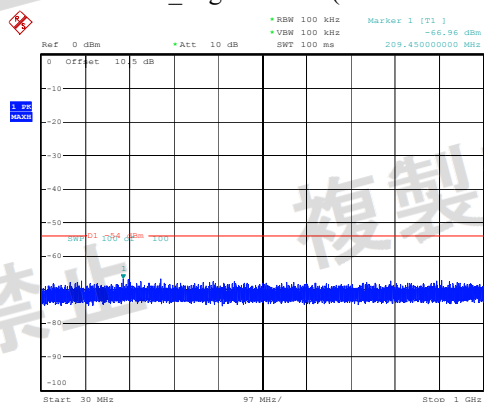
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:45:01

BLE 2M_Middle Channel(30MHz~1GHz)

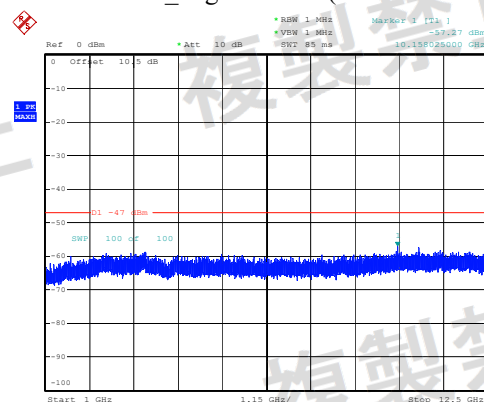
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:45:23

BLE 2M_Middle Channel(1GHz~12.5GHz)

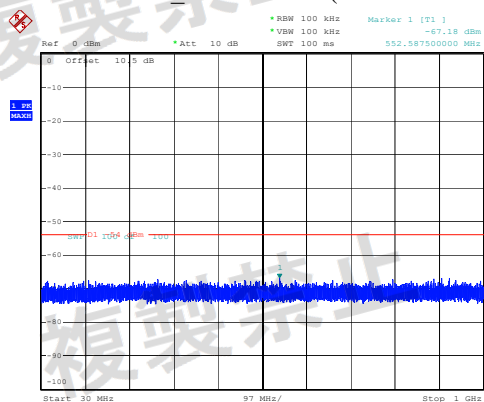
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:45:55

BLE 2M_High Channel(30MHz~1GHz)

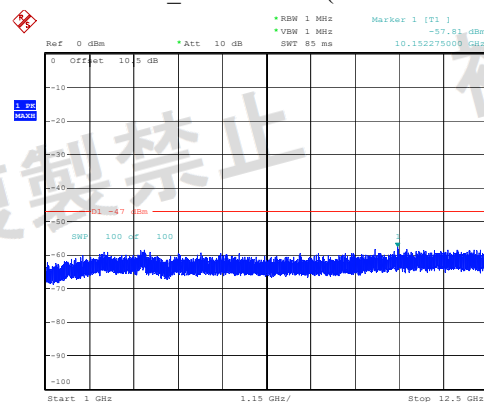
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:46:17

BLE 2M_High Channel(1GHz~12.5GHz)

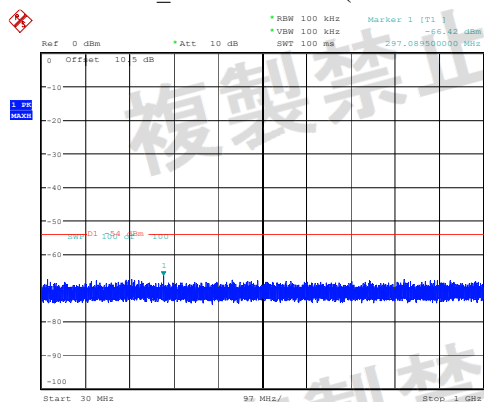
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:46:48

Test Condition: HV**BLE 2M_Low Channel(30MHz~1GHz)**

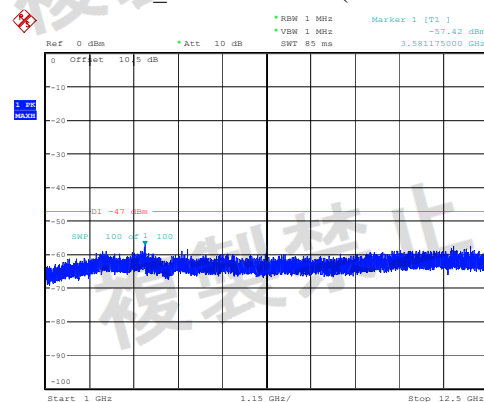
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:50:24

BLE 2M_Low Channel(1GHz~12.5GHz)

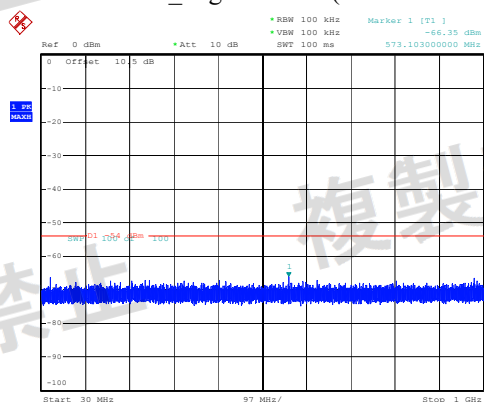
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:50:50

BLE 2M_Middle Channel(30MHz~1GHz)

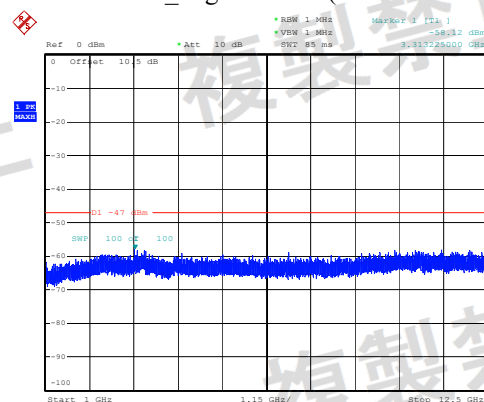
ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:51:21

BLE 2M_Middle Channel(1GHz~12.5GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:51:52

BLE 2M_High Channel(30MHz~1GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:52:15

BLE 2M_High Channel(1GHz~12.5GHz)

ProjectNo.:2501U26762E-RF Tester:Cheeb Huang
Date: 4.JUL.2025 14:52:46

Interference Prevention Function**Test Information:**

Sample No.:	34Q4-2	Test Date:	2025/07/04
Test Site:	RF	Test Mode:	Communicating
Tester:	Cheeb Huang	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	25.7	Relative Humidity: (%)	49	ATM Pressure: (kPa)	100.5
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CONSTRUCTION PROTECTION CONFIRMATION

Limit

The high-frequency section and modulation section of the radio equipment except for the antenna system shall not be capable of being opened easily.

Confirmation Result

The EUT has screws which can't be opened easily, please see the EUT photos.

EUT PHOTOGRAPHS

Please refer to the attachment 2501U26762E-RF External photo and 2501U26762E-RF Internal photo.

TEST SETUP PHOTOGRAPHS

Please refer to the attachment 2501U26762E-RF-07A-TSP Test Setup photo.

****END OF REPORT****